

**CERN Accelerator School on  
Free Electron Lasers and Energy Recovery Linacs**

# **Photon Beam Transport**

**Makina YABASHI**  
**RIKEN SPring-8 Center**  
**[yabashi@spring8.or.jp](mailto:yabashi@spring8.or.jp)**  
**June 8, 2016 @Hamburg**

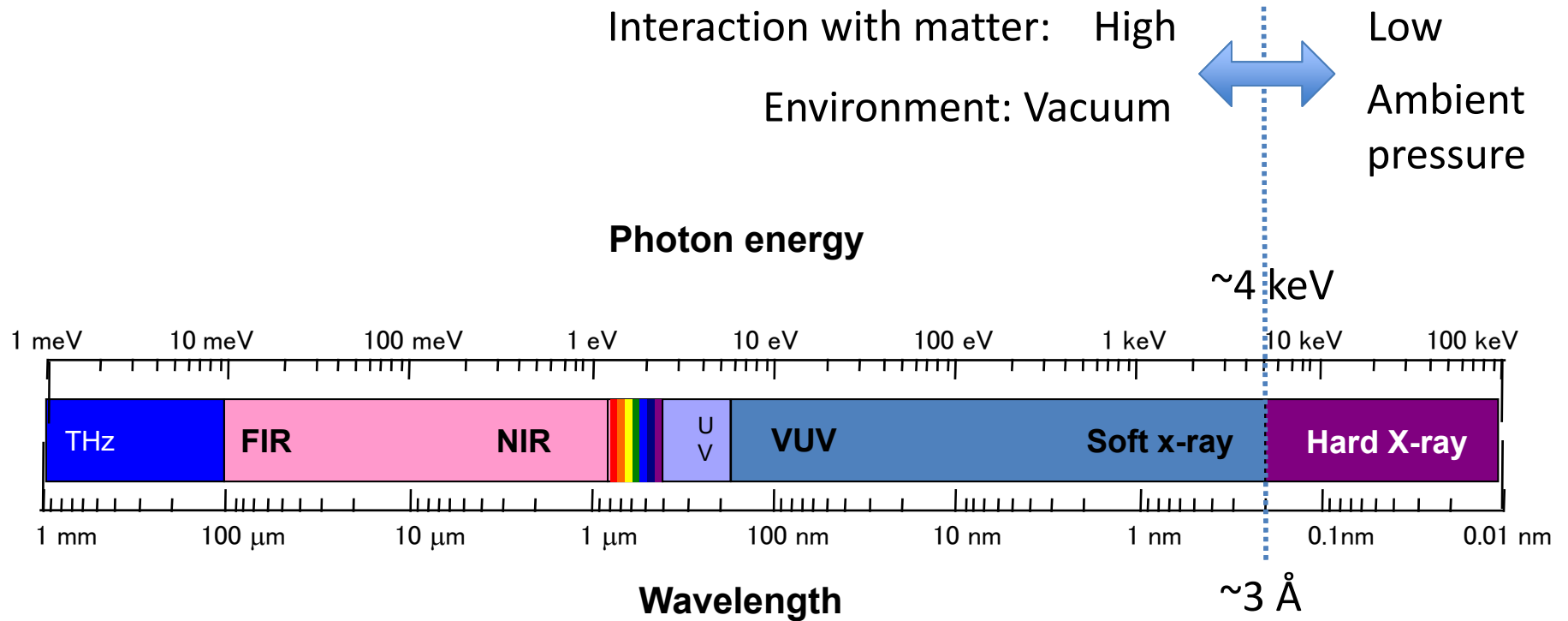
# Initial Remarks

- Photon beam transport = Photon beamline or X-ray beamline
- Not just “transport”
- Control & characterization of photon beam properties in 6-dimensional phase space (+ polarization)
- Key bridge & interface between accelerator and experiments

# Goal

- To provide key concepts on design and working principles of x-ray beamlines & optics
- To promote comprehensive understanding of both XFEL machine and x-ray beamline as a *light source complex*

# Hard or Soft ?



# Contents

1. Introduction: Brief history of photon beamlines for SR/XFEL
2. Preparatory: Phase space
3. X-ray optics
4. X-ray diagnostics
5. Design of beamline
6. Applications
  1. Photon-based undulator alignment
7. Summary

# Prototypical photon beamline at 1<sup>st</sup> gen. synchrotron sources ('70~)

## Synchrotron Radiation as a Source for X-ray Diffraction

G. ROSENBAUM & K. C. HOLMES

Max-Planck-Institut für Medizinische Forschung, Heidelberg

J. WITZ

Laboratoire des Virus des Plantes, Institut de Botanique de la Faculté des Sciences de Strasbourg, Strasbourg

Nature 1971

NATURE VOL. 230 APRIL 16 1971

DESY 7.5 GeV

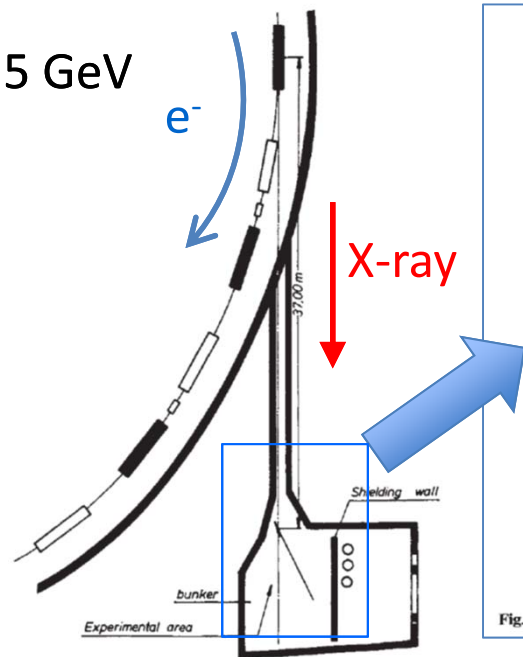


Fig. 1 The F41 bunker at DESY and its position with respect to the synchrotron.

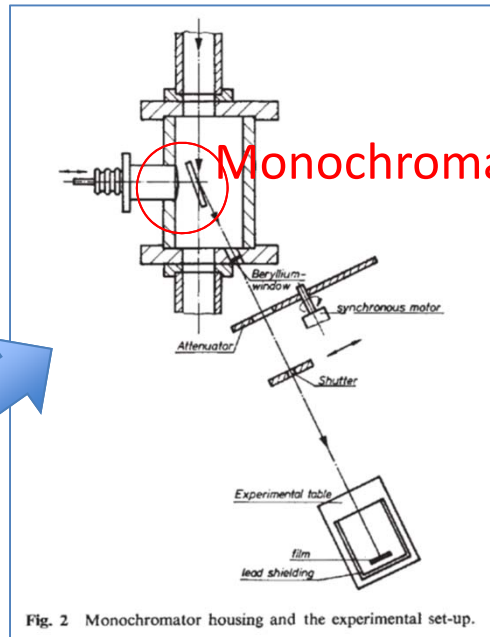
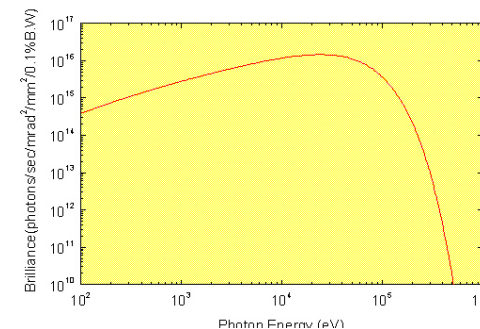


Fig. 2 Monochromator housing and the experimental set-up.

- Parasite to synchrotrons for high-energy physics
- Separation of experimental area from accelerator
- Key optics: monochromator (white spectrum of bending magnet source)





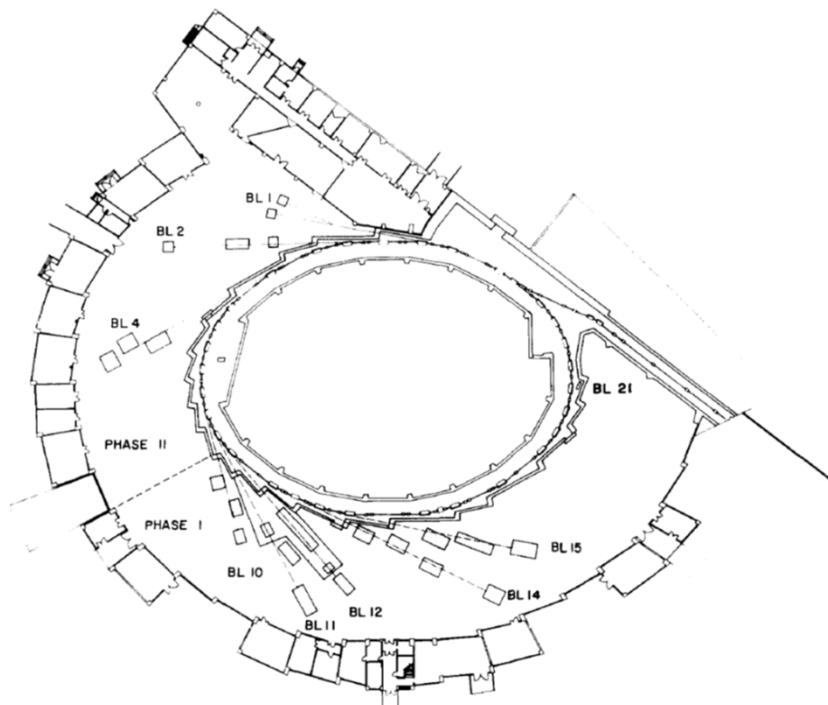
# Beamline at 2<sup>nd</sup> gen. SR ('80~)

Photon Factory (KEK, Japan)

Kohra & Sasaki, NIM 208 (1983) 23

K. Kohra, T. Sasaki / Present status of the Photon Factory

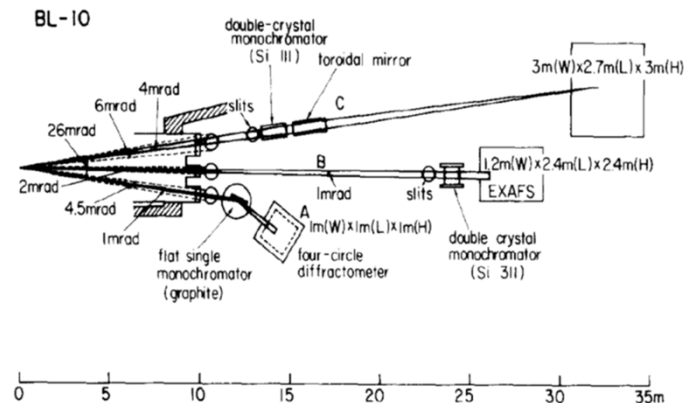
25



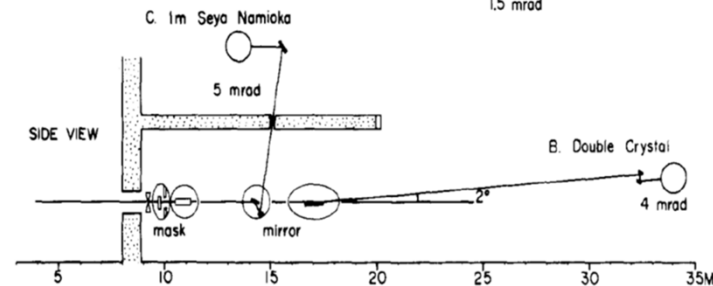
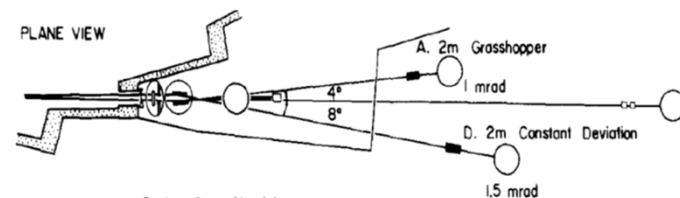
- Facility dedicated for utilizing X-rays
- Establishment of basic scheme of beamline
- Development of various X-ray optics (e.g., monochromator, focusing mirrors)
- Common optics installed into "optics hutch"

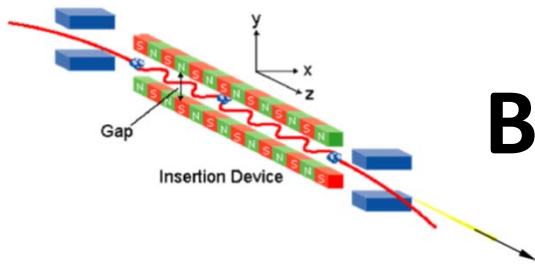
28

K. Kohra, T. Sasaki / Present status of the Photon Factory

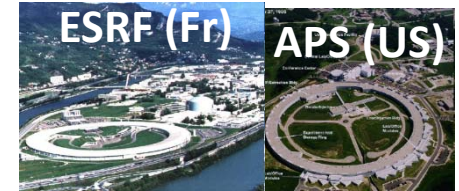


BL 11

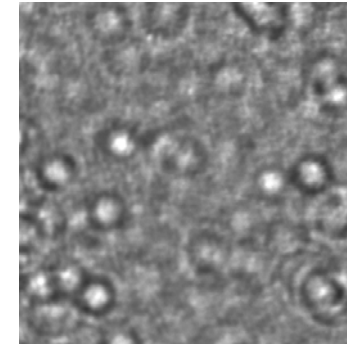




# Beamline at 3<sup>rd</sup> gen. SR

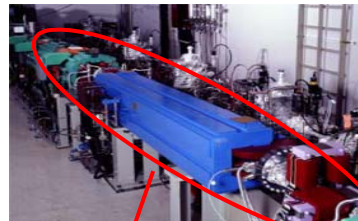


- Facility dedicated for utilizing **undulator radiation at low-emittance storage ring**
- Matured technologies
- “Coherence” much pronounced
- Higher quality required for x-ray optics to preserve coherent wavefront and to avoid speckles



Speckle patterns from conventional Be window (1-km BL @Spring-8)

Front-end

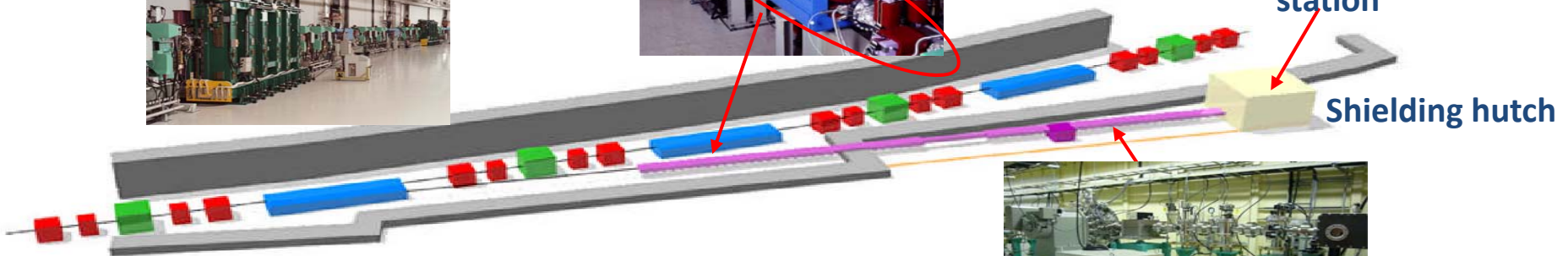


Undulator



Experimental station

Shielding hutch



Optics & transport

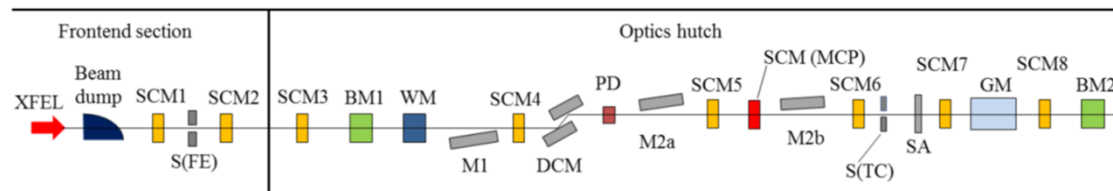
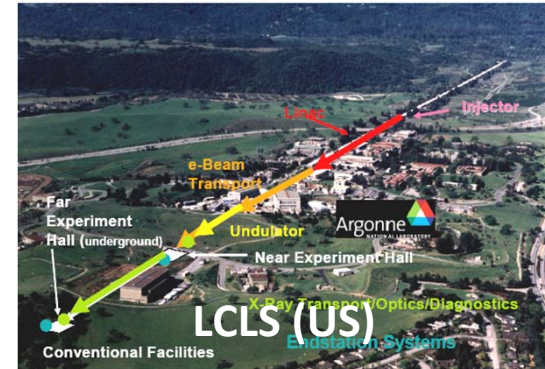
Typical configuration of undulator BL of SPring-8

Courtesy of Dr. Goto (SPring-8)



# Beamline at XFEL

- XFEL: Pulsed x-ray source with excellent transverse coherence
- Shot-to-shot changes in x-ray properties: **photon diagnostics** needed for conducting good experiments
- X-ray properties sensitive to machine parameters: BL provides useful information for achieving stable machine operation
- Enhanced connection between accelerator and BL



**Figure 3.** Photon diagnostic system on BL3. SCM1–8: screen monitor module; BM1,2: thin-foil beam monitor; WM: thin-foil wavelength monitor; GM: scattering-based gas monitor; SCM (MCP): screen monitor with a micro-channel-plate image intensifier.

Beamline configuration of SACLA XFEL  
 Tono et al, New J Phys **15** (2013) 083035

# Summary: Development on x-ray beamline



- Prototypical BL for parasitic use
- Separation from accelerator
- Establishment of basic scheme for dedicated use
- High-quality optics for coherent x-ray applications
- Photon diagnostics for both users & machine
- Closer connection to accelerator

# Contents

1. Introduction: Brief history of photon beamlines for SR/XFEL
- 2. Preparatory: Phase space**
  1. Transverse phase space & coherence
  2. Longitudinal phase space
3. X-ray optics
4. X-ray diagnostics
5. Design of beamline
6. Summary

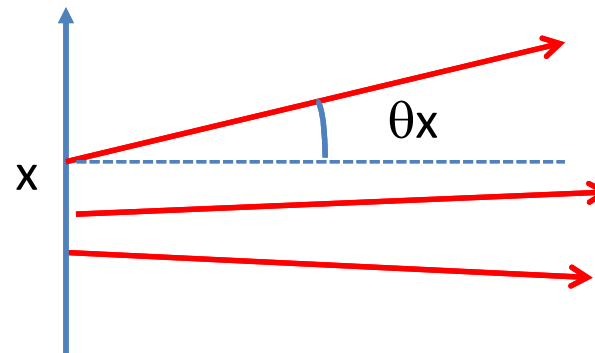
# Phase space

Role of photon beamline: “Control & characterization of photon beam properties in *6-dimensional phase space* (+ polarization)”

Transverse x 4

Position:  $(x, y)$

Angle:  $(\theta_x, \theta_y)$



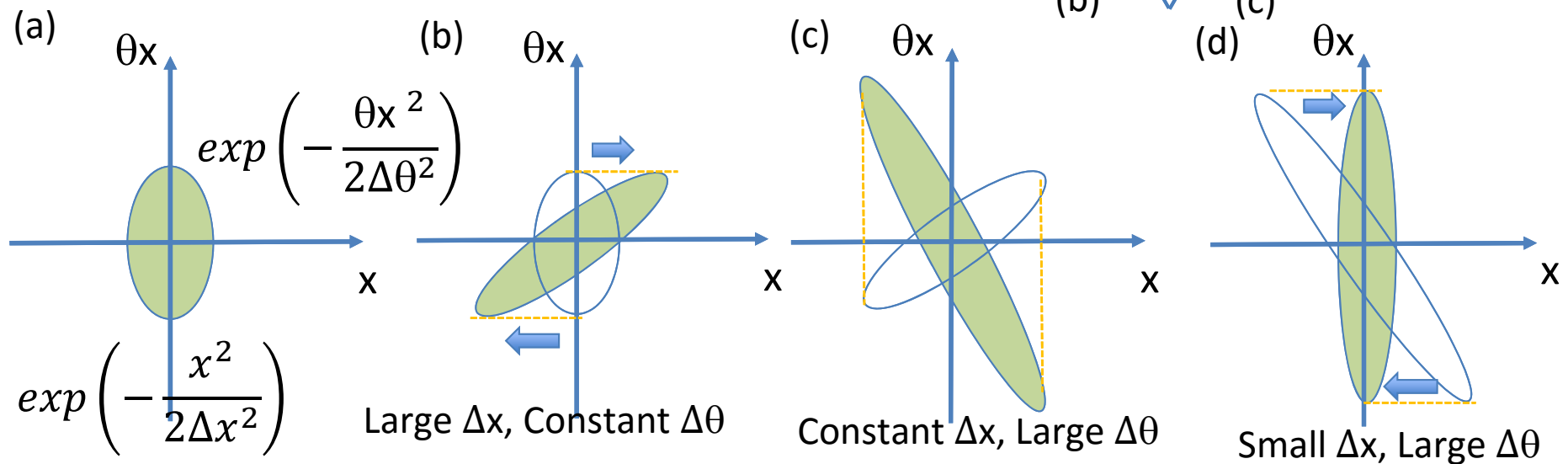
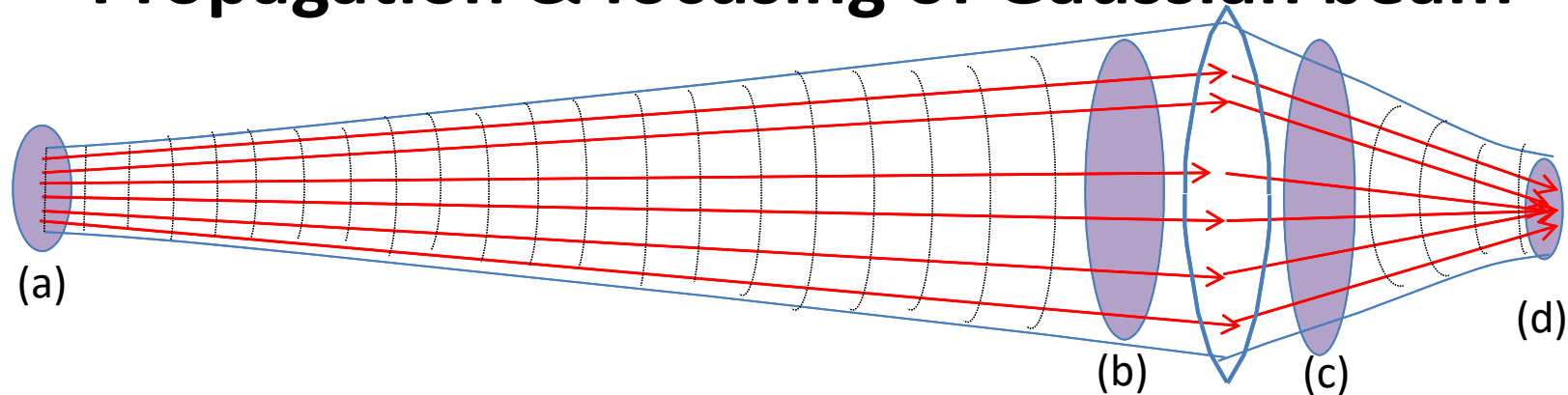
Longitudinal x 2

Frequency (=photon energy or wavelength)  $h\nu$  ( $=hc/\lambda$ )

Time:  $t$

Brilliance: photon density in 6-D phase space

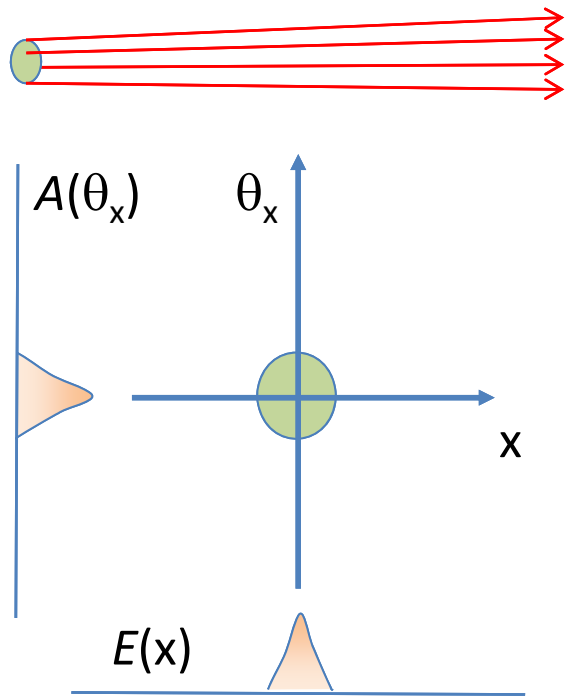
# Transverse phase space: Propagation & focusing of Gaussian beam



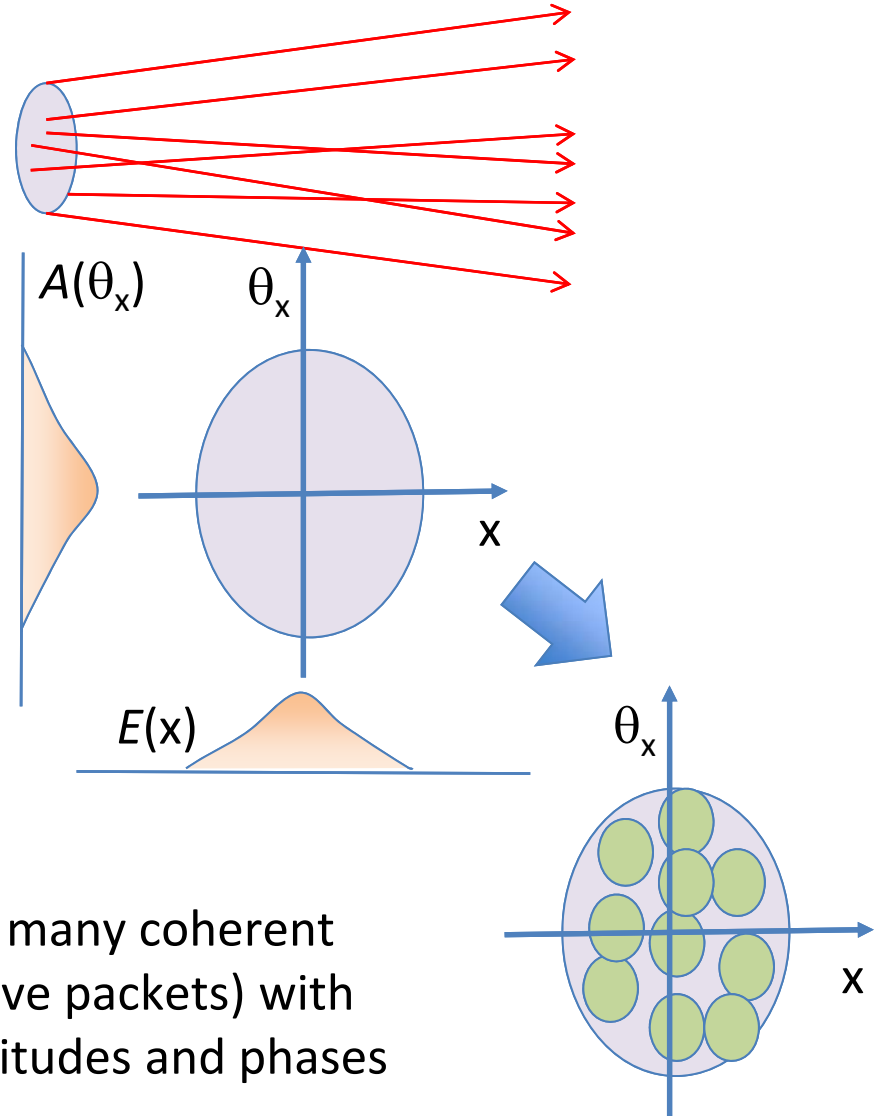
- Area of ellipse is called **emittance**
- Emittance is conserved with optical transformation
- Minimum emittance:  $\Delta x \cdot \Delta\theta \sim C \cdot \lambda$  **Diffraction-limited condition**  
e.g., XFEL:  $\Delta x \cdot \Delta\theta \sim 10 \text{ um} \cdot 1 \text{ urad} \sim 1e-11 \text{ um} \sim 1 \text{ \AA}/4\pi$

# Distribution in transverse phase space ( $x-\theta$ )

Small size/small divergence

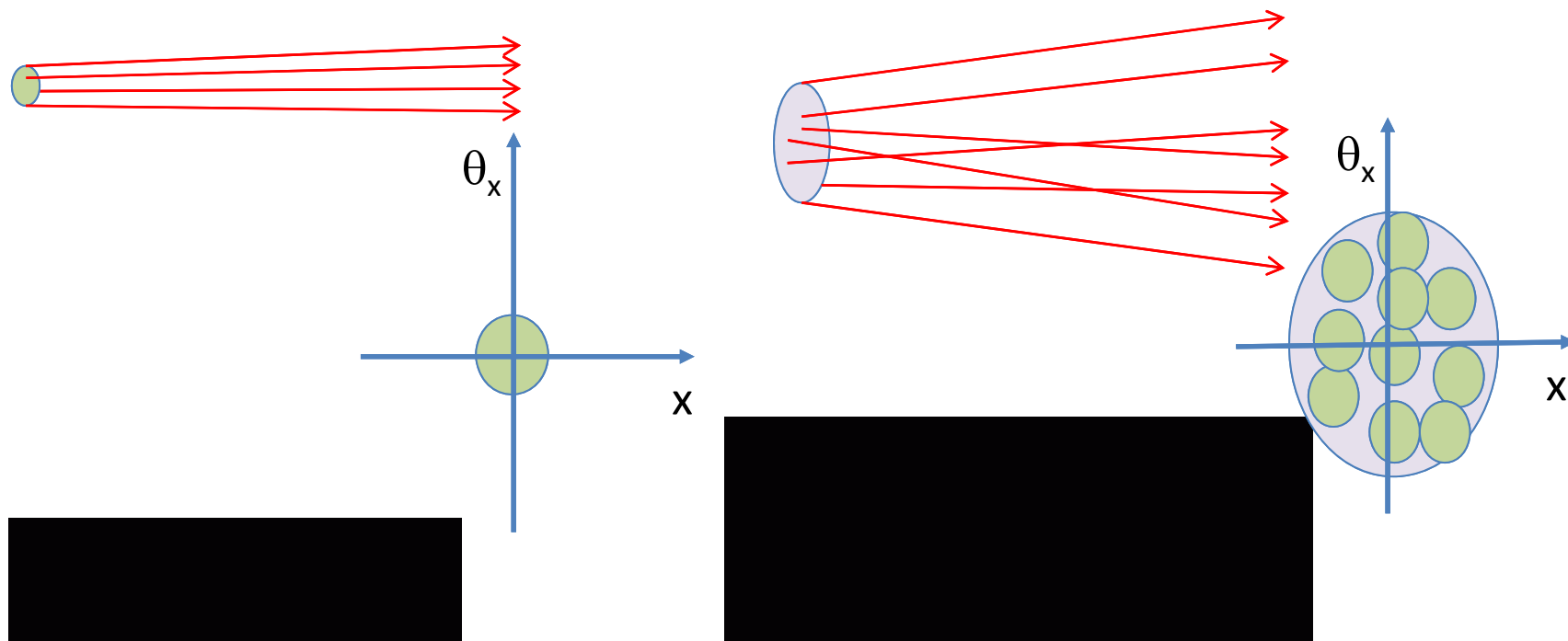


Large size/large divergence



Composed of many coherent elements (wave packets) with random amplitudes and phases

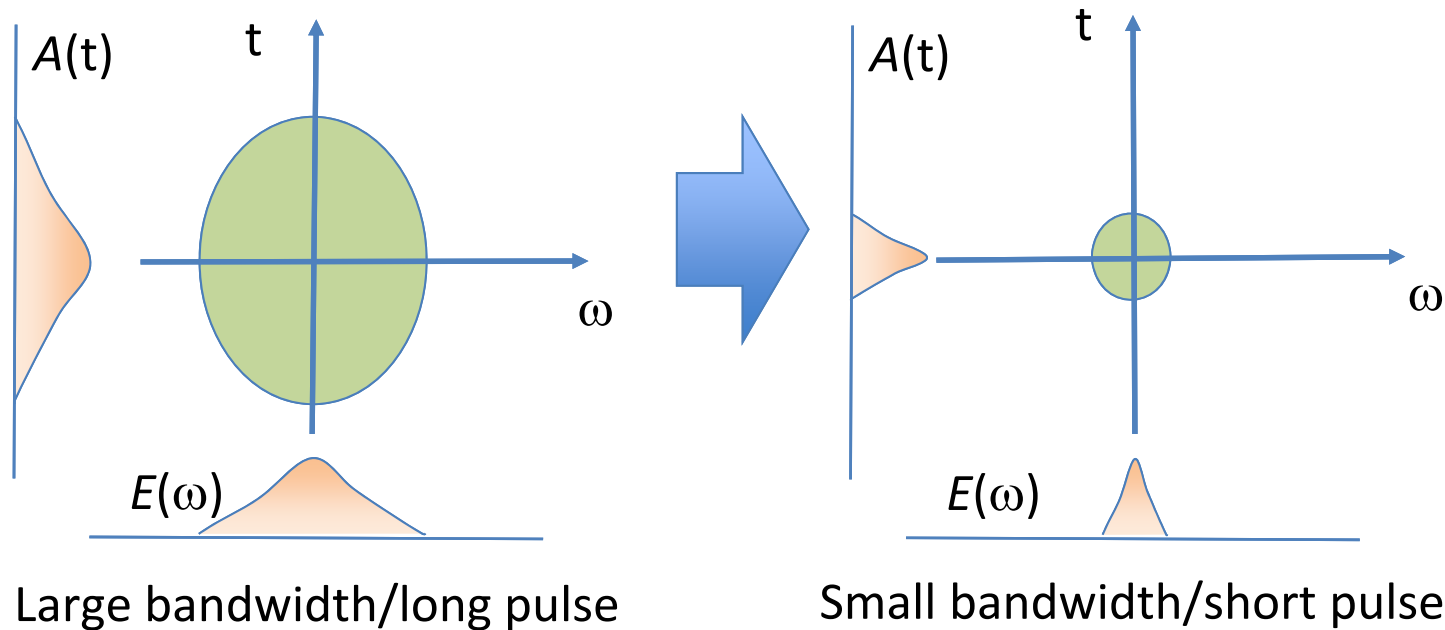
# Transverse coherence



Full transverse coherence  
XFEL generates transversely  
coherent x-rays

Partially transverse coherence

# Distribution in longitudinal phase space



- Minimum area:  $\Delta\omega \cdot \Delta t \sim \lambda/2\pi$  **Fourier-limited condition**
- X-ray pulse can be compressed into very short duration ( $\lambda/c \sim 1\text{e-}18\text{ s} = 1\text{ as}$ )



# Short summary

- Phase space is a useful concept for intuitive understanding of photon beam properties and optics design

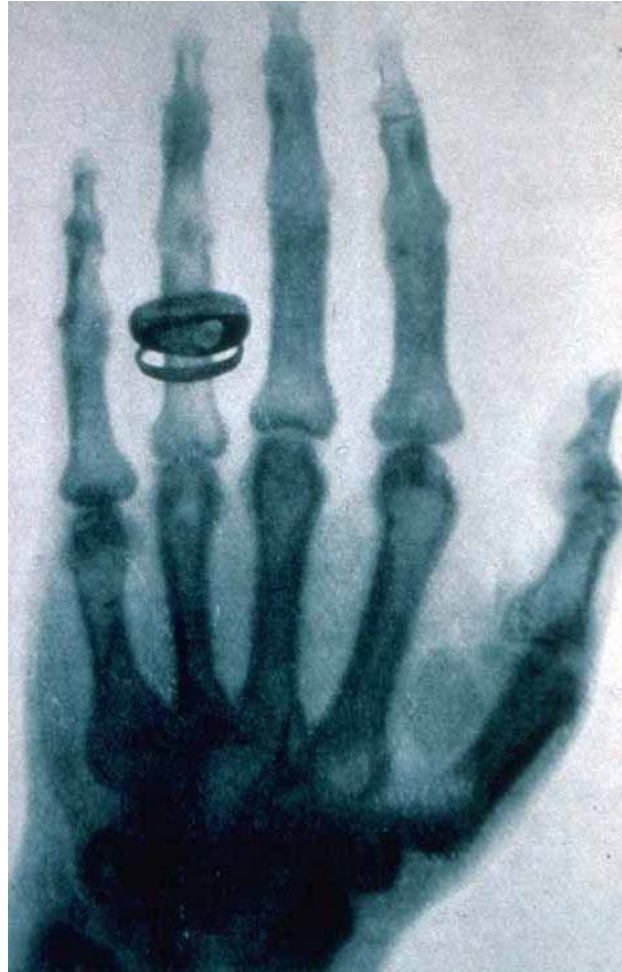
## References:

- K. J. Kim, “Characteristics of synchrotron radiation” AIP Conf. Proc. 184 (1989) 565: Excellent introduction of synchrotron light sources with usage of phase space
- M. Born & E. Wolf, “Principles of Optics: Electromagnetic Theory of Propagation, Interference and Diffraction of Light,” 7<sup>th</sup> ed. Cambridge University (1999); standard textbook on general optics and interference
- J.W. Goodman, “Statistical optics” A Wiley-Interscience Publication, New York, (2000); facilitate essential understanding of coherence and statistical optics
- A. Yariv & P. Yeh, “Photonics: Optical Electronics in Modern Communication (The Oxford Series in Electrical and Computer Engineering)”, Oxford Univ. Press, (2006): One of the most standard textbooks on optics and beam physics

# Contents

1. Introduction: Brief history of photon beamlines for SR/XFEL
2. Preparatory: Phase space
- 3. X-ray optics**
  1. Interaction of x-ray to matter
  2. Optical elements
  3. Function
4. X-ray diagnostics
5. Design of beamline
6. Summary

# X-ray optics



X-rays:

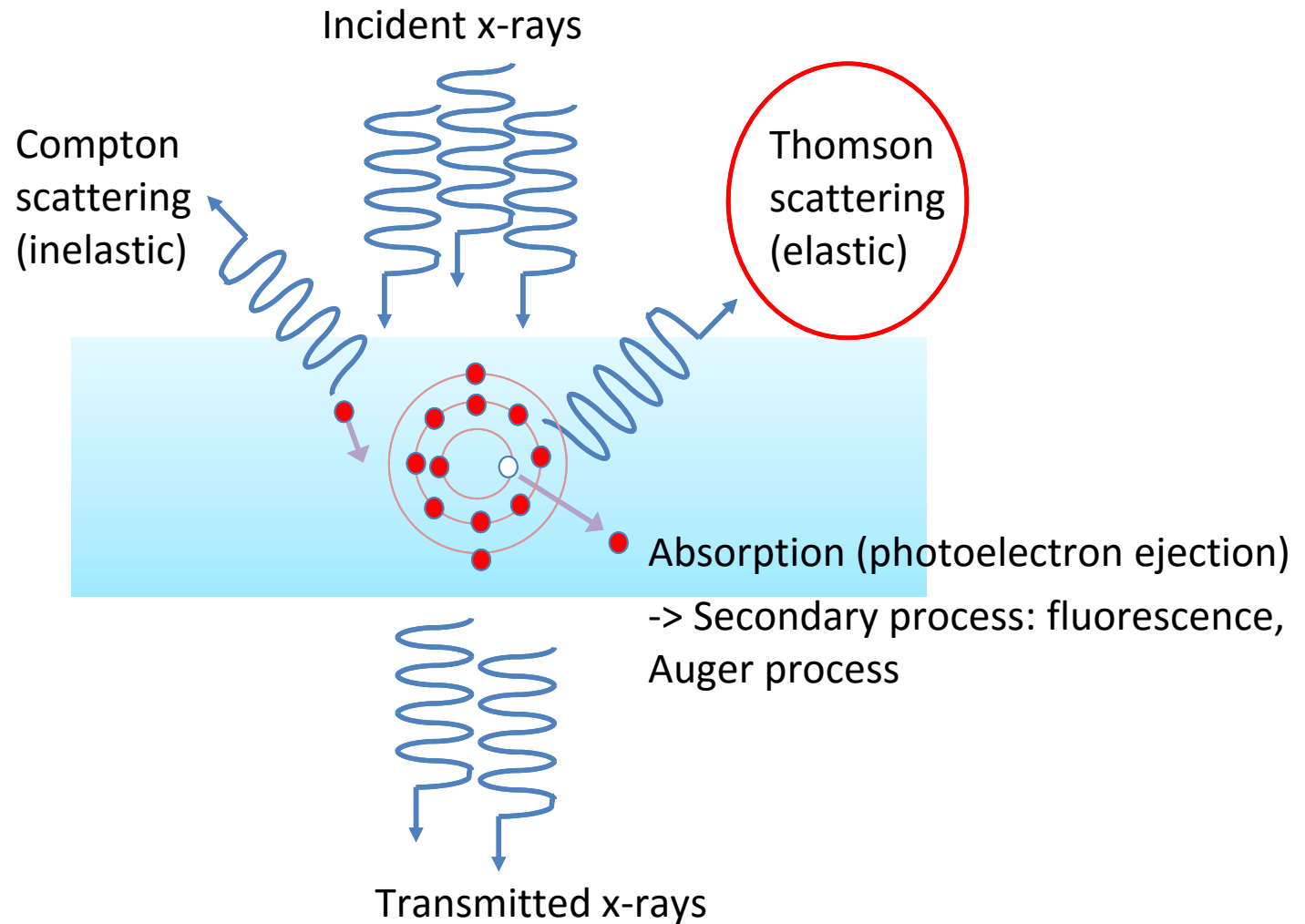
High penetration to materials

Small (but **non-zero**)  
interactions with matters

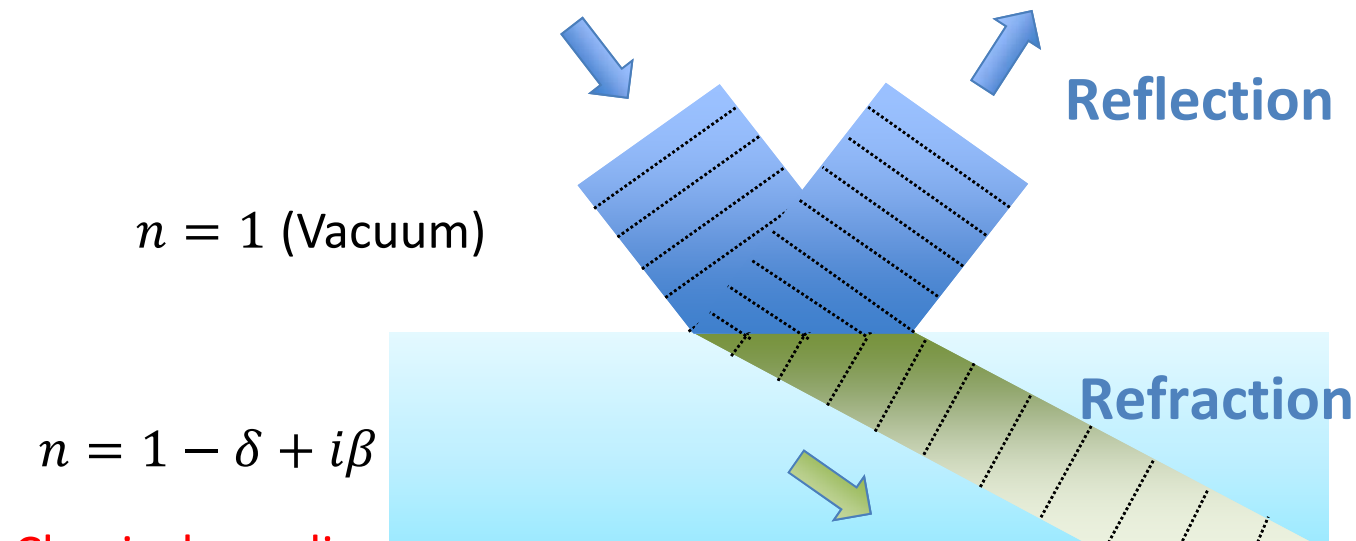
Design of x-ray optics is feasible,  
but not straightforward

*We could not use magnetic forces*

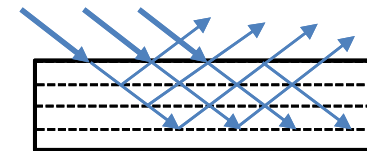
# Major interactions of x-ray with matter



# Key optical property: Refractive index



Diffraction (with periodic media)



Classical e-radius  
Wavelength

Density of electrons

Small correction of anomalous effect

$$\delta = \frac{\lambda^2 r_e (Z + f') N}{2\pi} \quad \beta = -\frac{\lambda^2 r_e f'' N}{2\pi}$$

$$\delta \sim \frac{(10^{-10} \text{ m})^2 10^{-15} \text{ m}^{-1} \cdot 10 \cdot 10^{30} \text{ m}^{-3}}{10} \sim 10^{-5}$$

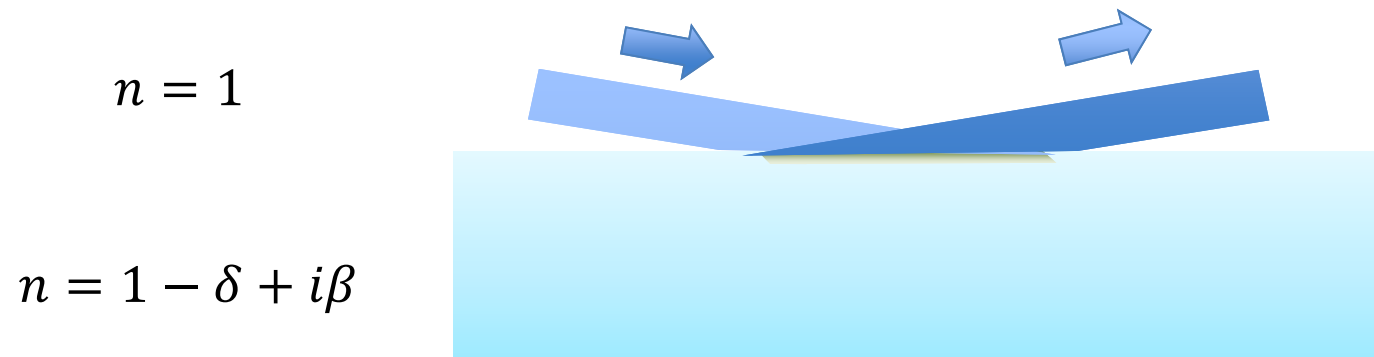
$\delta, \beta \sim 1\text{e-}5 \text{ to } 1\text{e-}7 \text{ at } \lambda \sim 1 \text{ \AA}$   
 $n < 1$

Derivation: harmonic oscillations of electrons in atoms generate secondary wave  
Integration of many secondary waves

# Contents

1. Introduction: Brief history of photon beamlines for SR/XFEL
2. Preparatory: Phase space
- 3. X-ray optics**
  1. Interaction of x-ray to matter
  - 2. Optical elements**  
Reflective/Refractive/Diffractive
  3. Function
4. X-ray diagnostics
5. Design of beamline
6. Summary

# Reflective optics: Total reflection at surface with grazing angle incidence



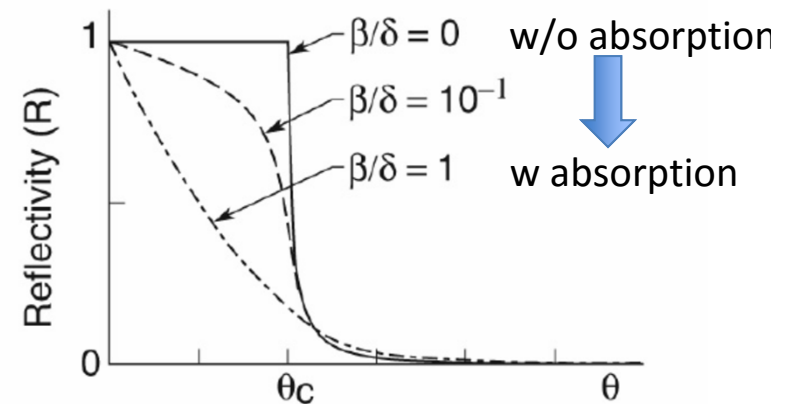
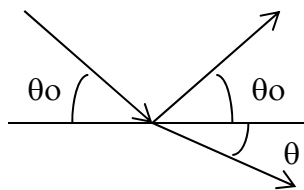
Refraction angle: Snell's law  $n = \frac{\cos\theta_0}{\cos\theta}$

Reflectivity/transmissivity at interface:  
Fresnel's formula

Total reflection ( $\theta = 0$ ) with incident angle smaller than  $\theta_c$

$$1 - \delta = \cos\theta_c = 1 - \frac{\theta_c^2}{2}$$

$$\rightarrow \theta_c = \sqrt{2\delta} \sim 1e-3 \text{ (rad)}$$



# Reflective optics: X-ray mirror

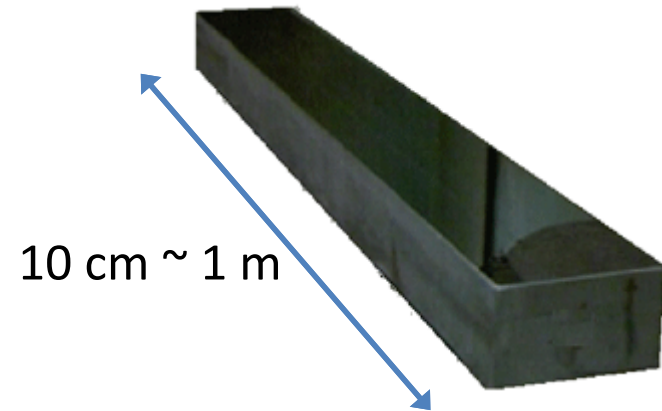
$\theta_C \sim \text{mrad}$

-> give small deflection angle to incident x-rays

(beam steering)

-> focusing with specific surface shape

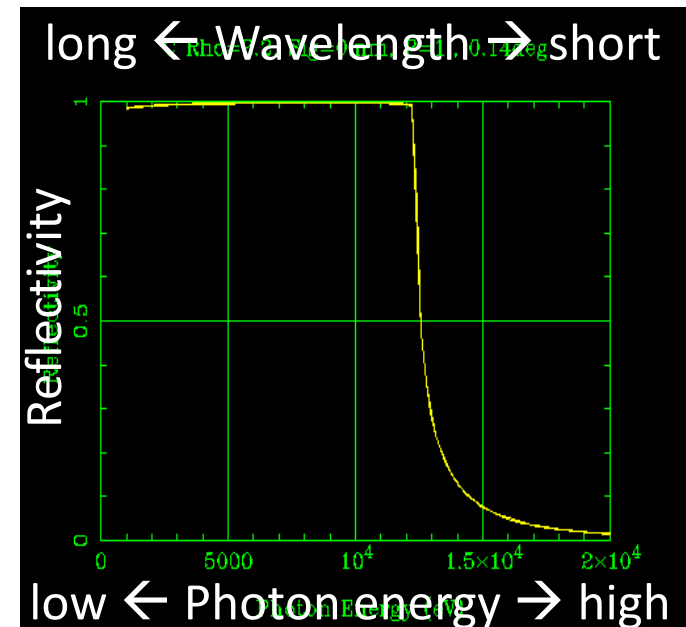
-> long length required along the meridional direction (1 mrad x 1 m length = 1 mm acceptance)



$$\theta_C = \sqrt{2\delta} \sim \sqrt{\frac{2\lambda^2 r_e (Z + f') N}{2\pi}} = A \cdot \lambda c \sqrt{\rho}$$

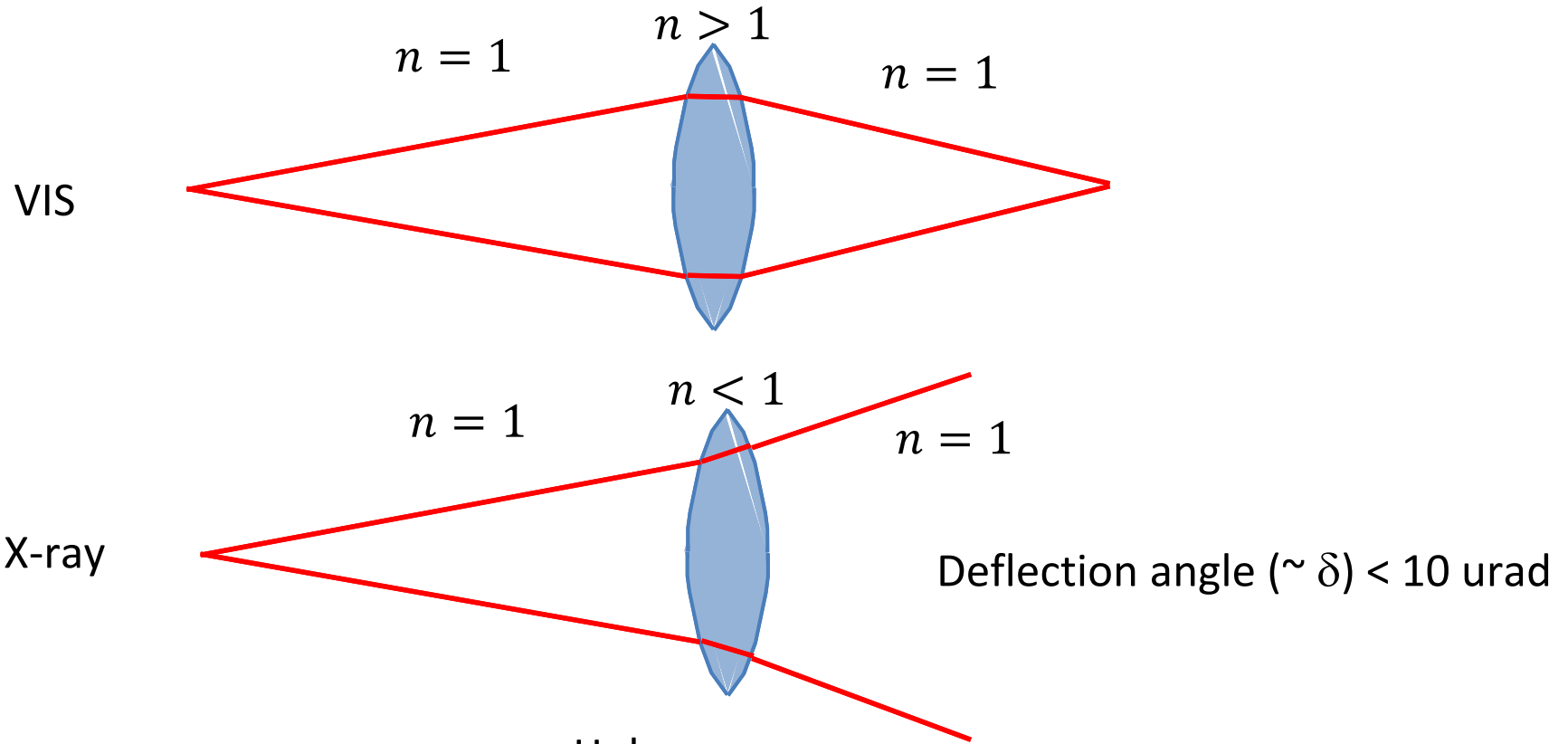
-> Total reflection only for  $\lambda > \lambda_C$  for fixed  $\theta_C$   
(low-pass filter in frequency domain)

-> reject higher harmonics or gamma-rays from source





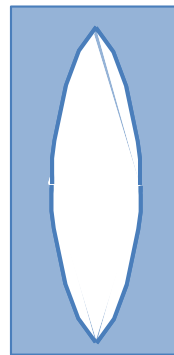
# Refractive optics: lens



Hole

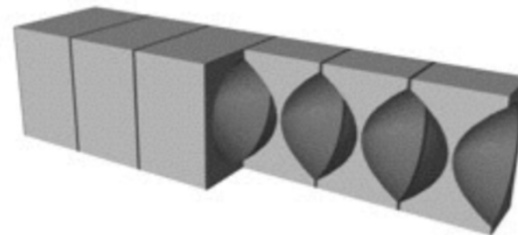
Compound Refractive Lenses  
(CRL)

A. Snigirev et al., Nature  
384 (1996) 49



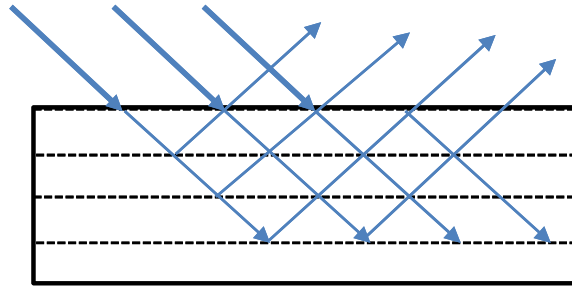
+

Stacking in array

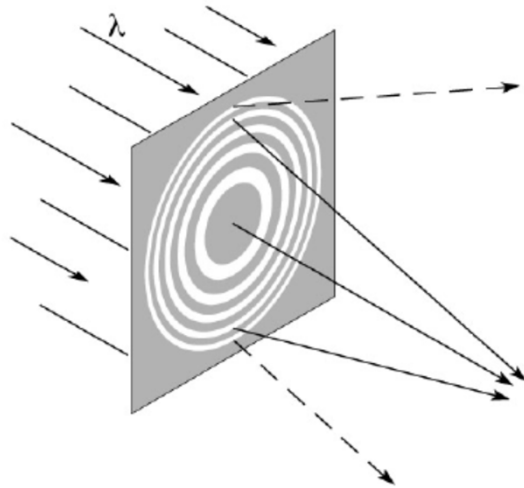


# Diffractive optics

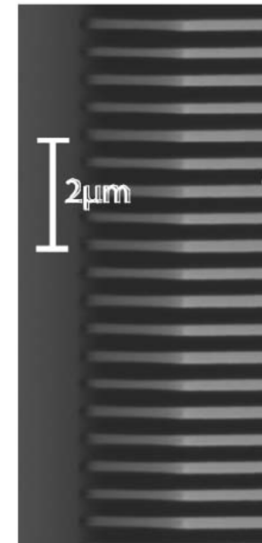
Perfect crystal  
Silicon, diamond




Fresnel Zone Plate  
(FZP)



Grating



# Contents

1. Introduction: Brief history of photon beamlines for SR/XFEL
2. Preparatory: Phase space
- 3. X-ray optics**
  1. Interaction of x-ray to matter
  2. Optical elements
  - 3. Function**  
Focusing/monochromator/speckle-free
4. X-ray diagnostics  *e.g., Q-magnet nor chicane ...*
5. Design of beamline
6. Summary

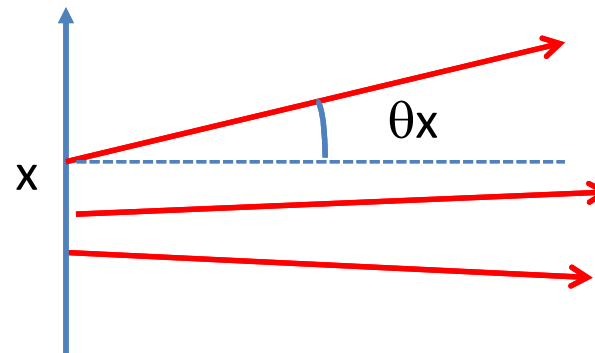
# Function of x-ray optics

Tailor of photon beam properties in 6-dimensional phase space (+ polarization)

Transverse x 4

Position:  $(x, y)$  ← focusing

Angle:  $(\theta_x, \theta_y)$



Longitudinal x 2

Frequency (=photon energy or wavelength)  $h\nu$  ( $=hc/\lambda$ )

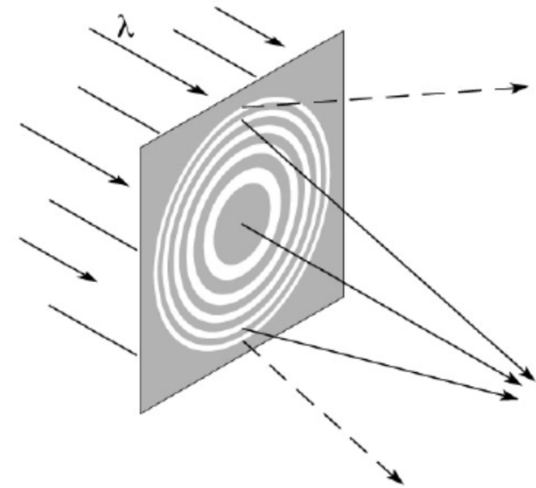
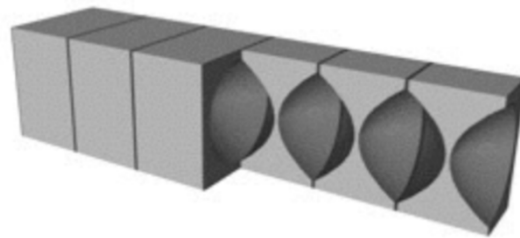
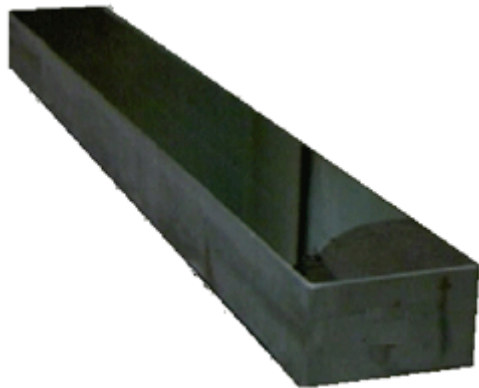
← monochromator

Time:  $t$

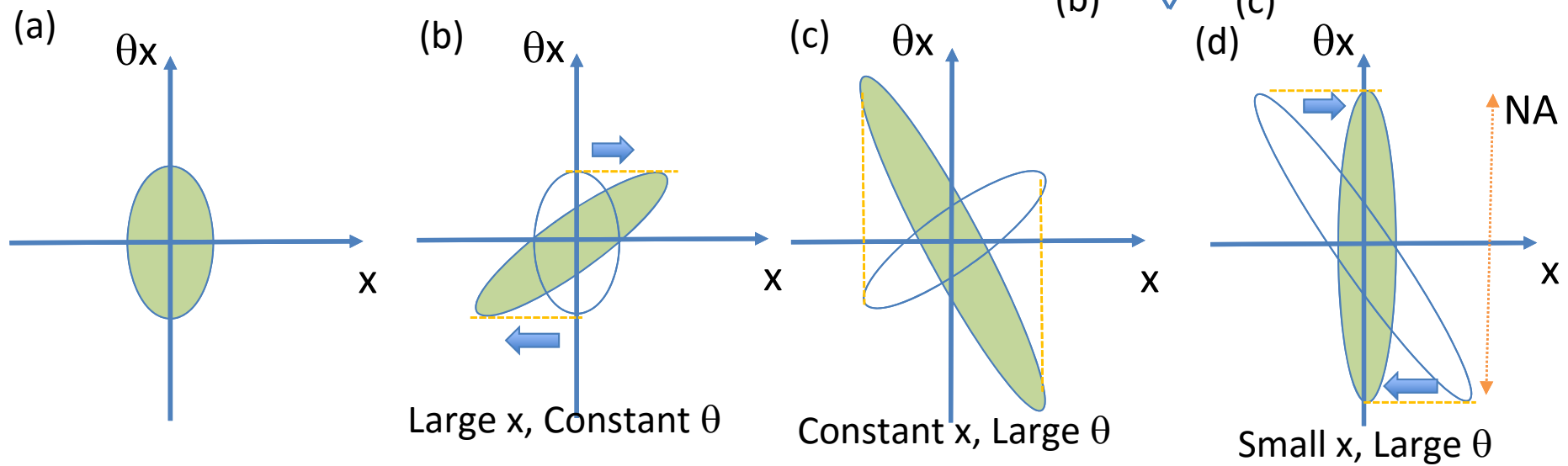
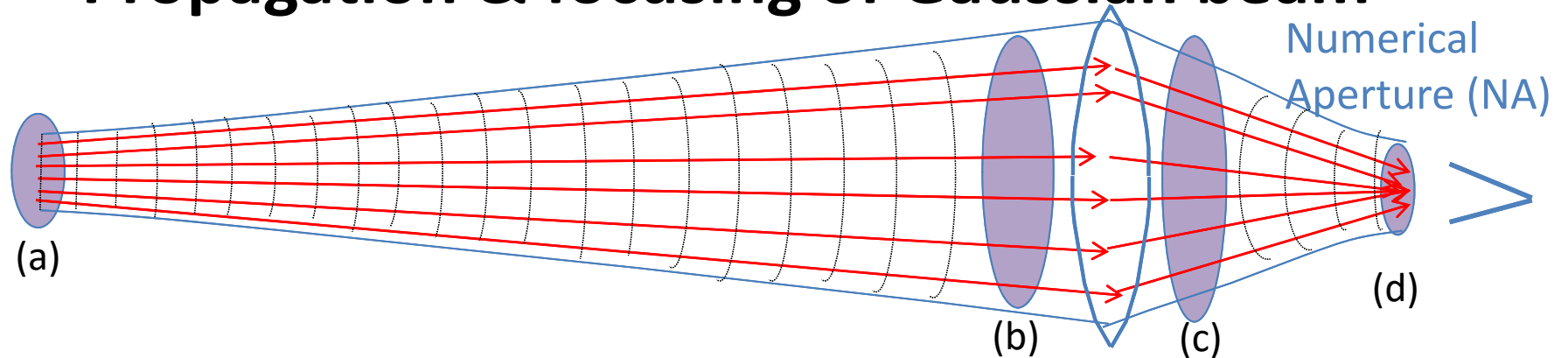
Brilliance: photon density in 6-D phase space

# Function (I): Focusing

- Focusing capability is one of the most essential functions in x-ray microscopy and analysis
- Reflective, refractive, diffractive optics are used for focusing



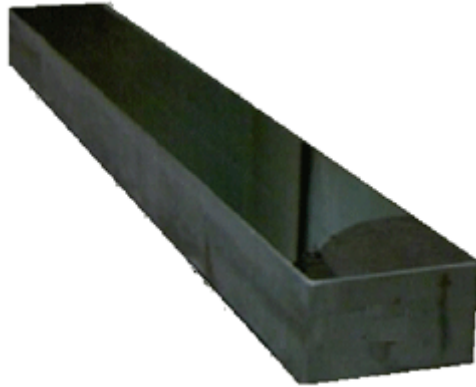
# Transverse phase space: Propagation & focusing of Gaussian beam



- Smaller beam size, larger divergence (NA)  $\Delta x \cdot NA \sim \lambda$   
 → Large NA is required for generating small spot  
 X-ray beam can be focused into small spot ( $\sim \text{nm}$ )

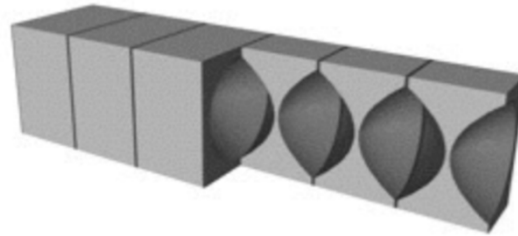
# Comparison

Reflective



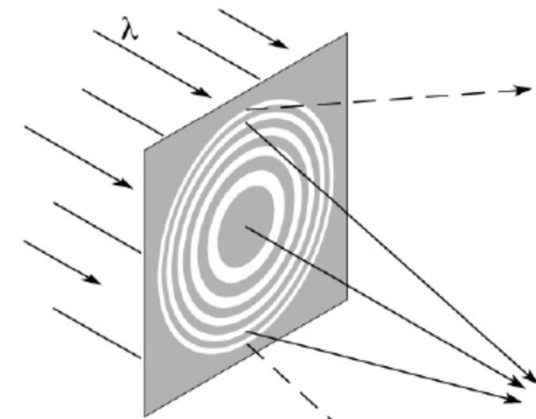
- High efficiency ( $R > 70\%$ )
- Achromatic
- Small spot (7 nm)
- Fabrication complexity
- Small deflection of exit beam

Refractive



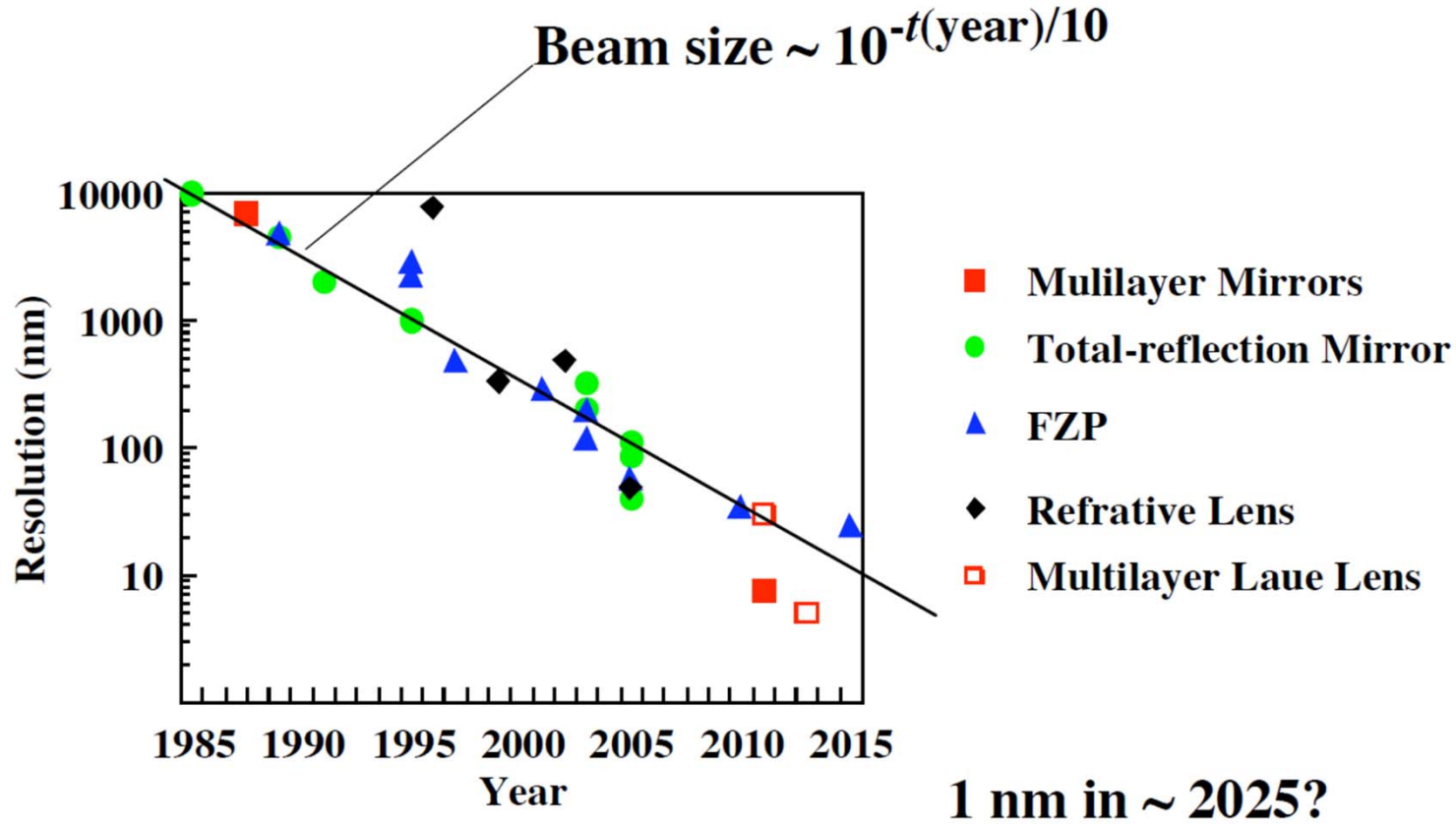
- Operation feasibility
- Tunable focal length with changing # of stack
- Prefer to high energy x-rays ( $> 10$  keV) for reducing absorption

Diffraction



- Utilized in various types of soft x-ray microscopy
- Variation in patterns for phase control
- Compact design
- Fabrication complexity
- Efficiency limited by diffraction
- Bandwidth:  $\Delta\lambda/\lambda \sim 1/N$

# Trend of spot size



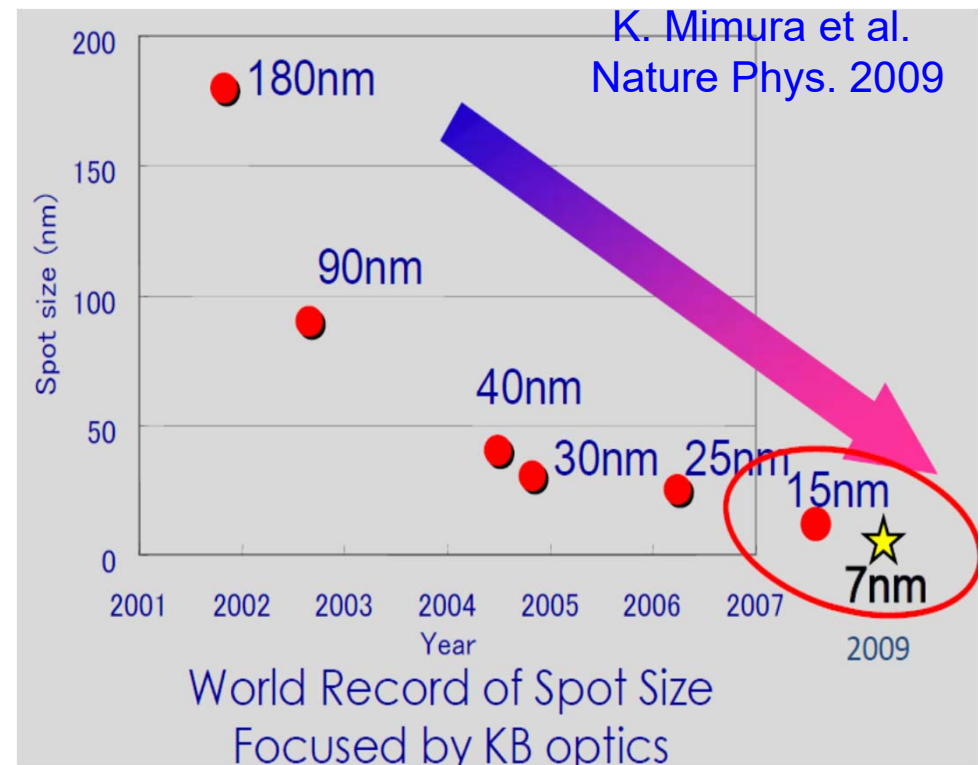
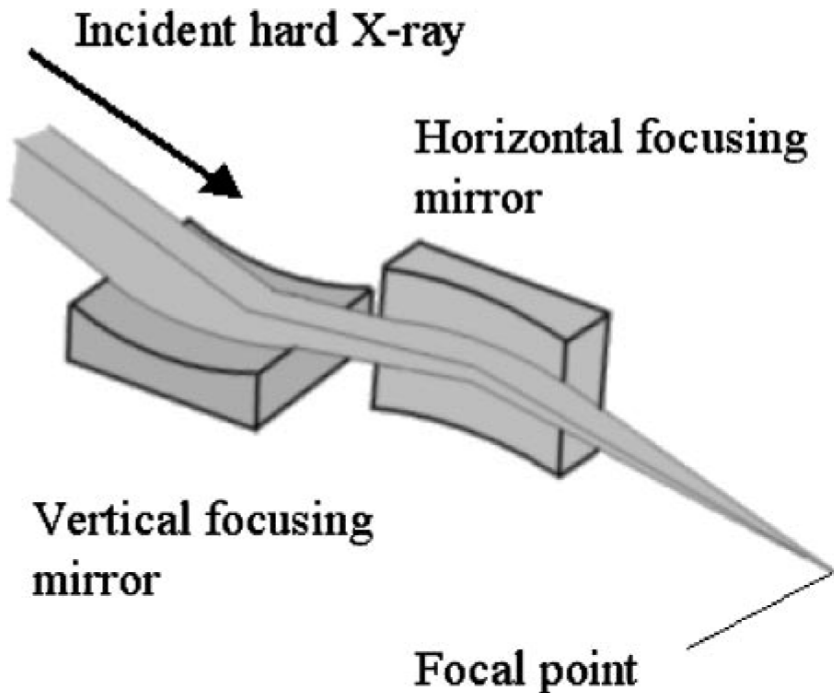
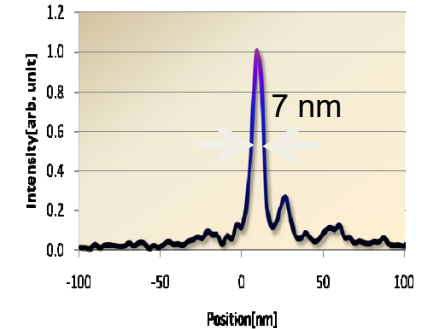
## Resolution Trend of X-ray Microbeam

Courtesy of Dr. Yoshio Suzuki



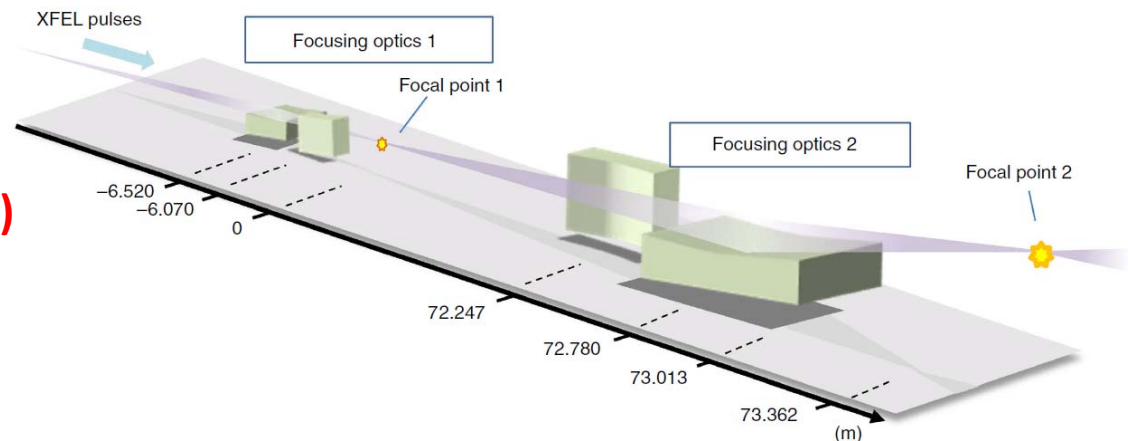
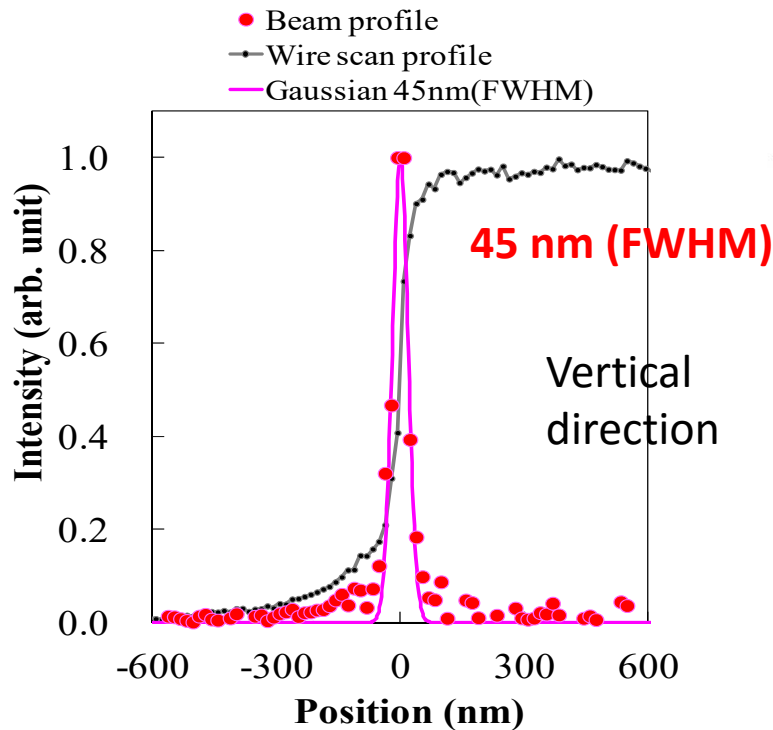
# Focusing with mirrors

- Total reflection only working at grazing incidence condition
- Combination of two cylindrical mirror was first proposed by Kirkpatrick and Baez (JOSA, 1948)
- High reflectivities, but challenging in fabrication
- Cylindrical  $\rightarrow$  elliptical shape for generating small spot without aberration
- Technological developments since 2000 for achieving accurate figure shape



# Nano-focusing for XFEL

- Focusing of XFEL → production of extremely high intensity of X-ray pulse
- Low divergent beam ( $\sim \mu\text{rad}$ ) → small beam size at focusing optics → limitation of NA → difficulty in achieving small focus
- Combination of two focusing system: first one for enlarging divergence and beam size, and second one for small focusing
- 50 nm size achieved with extreme intensity over  $10^{20} \text{ W/cm}^2$



# Achievement of Hard X-ray Cu-K $\alpha$ atomic laser

9 keV (pump) &  
8 keV (seed)

Two-stage  
focusing

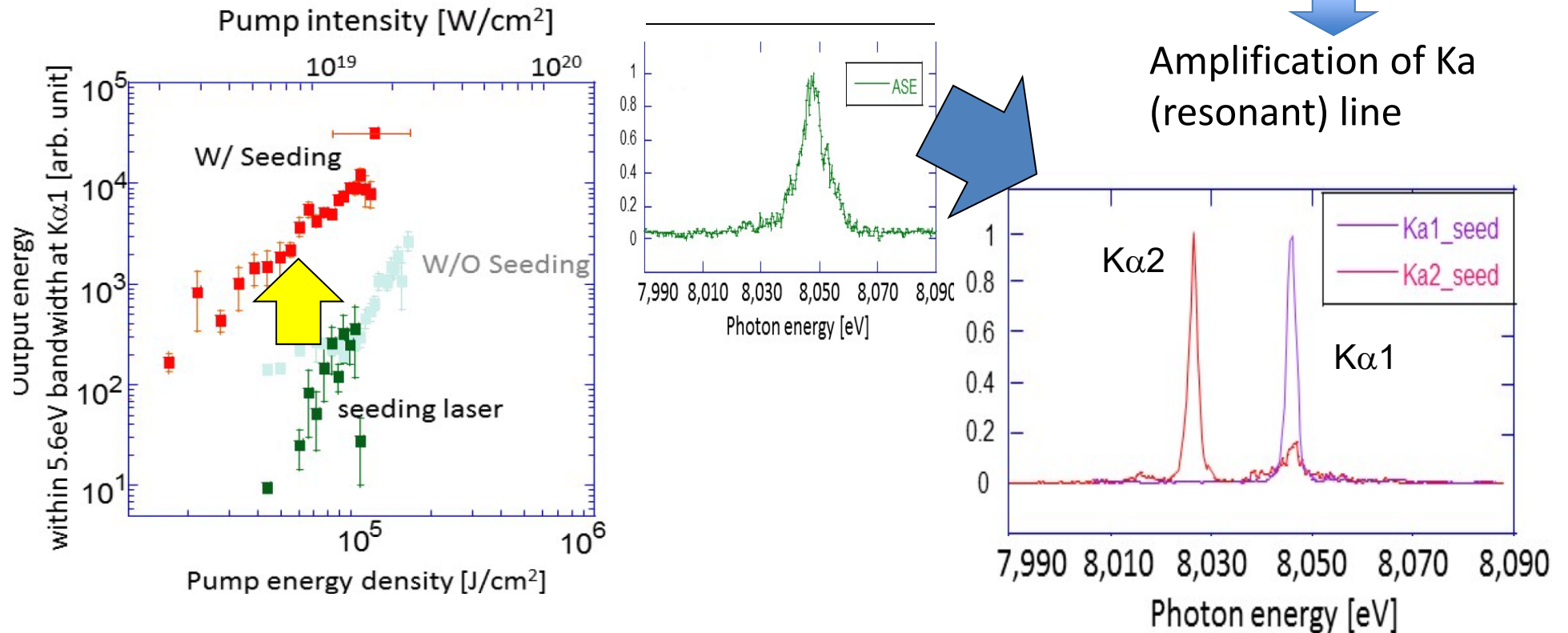
Yoneda *et al.*,  
*Nature* **524** 446  
(2015)

8 keV

Intense pump x-rays  
strip K-shell electrons  
and generate  
“population inversion:

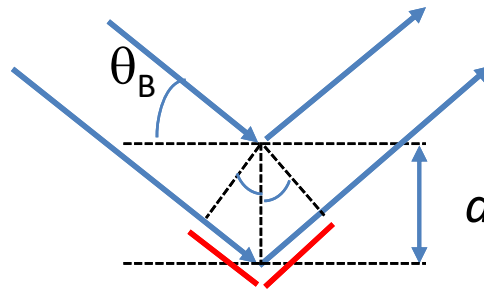
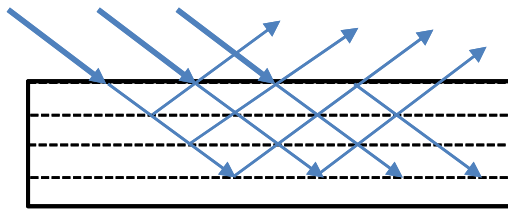
Cu foil

Amplification of K $\alpha$   
(resonant) line



# Function (II): Monochromator

- Monochromator is the key optical device in SR beamlines
- Energy resolution (typically several percent for SR) is insufficient for most x-ray applications (crystallography, spectroscopy, etc.)
- Perfect crystals are widely used as monochromator optics



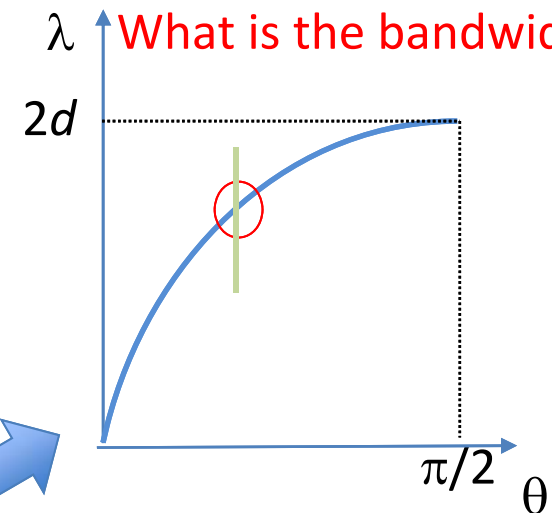
Path difference  $\delta = 2d\sin\theta_B$   
Diffraction occurred at  $\delta = n\lambda$

Bragg's law:  $\lambda = 2d\sin\theta_B$

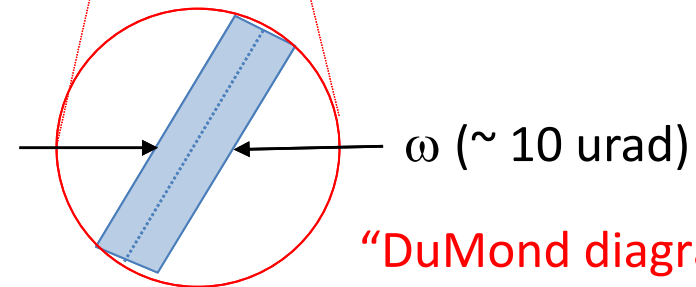
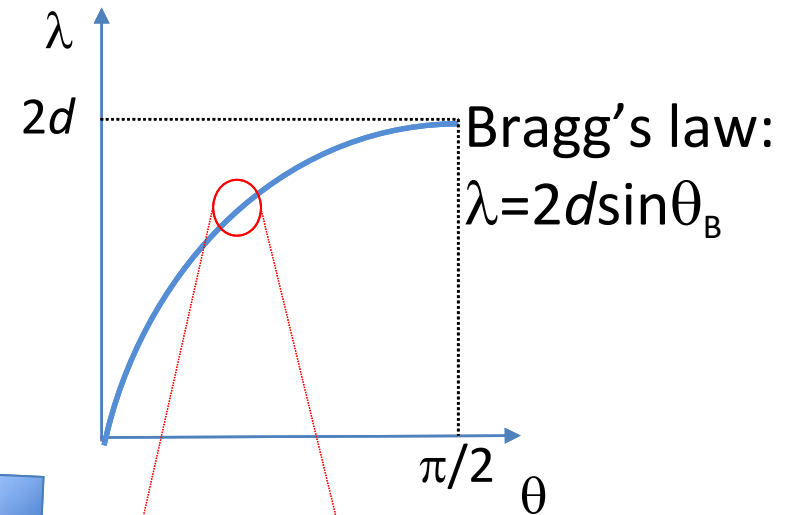
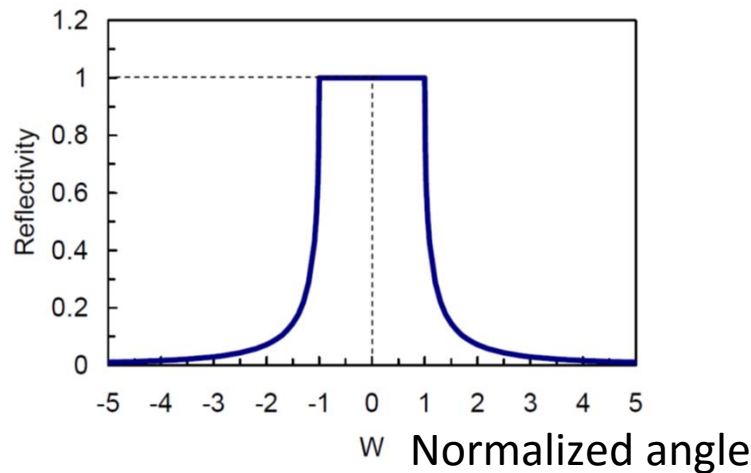
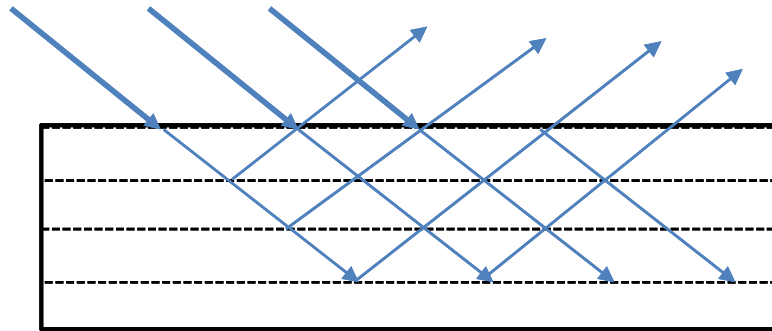
→ Monochromator based on angular-wavelength relationship

Linewidths are not infinitely small →

What is the bandwidth ?



# Representation of perfect-crystal monochromator in angular-frequency ( $\theta$ - $\lambda$ ) phase space



“DuMond diagram”

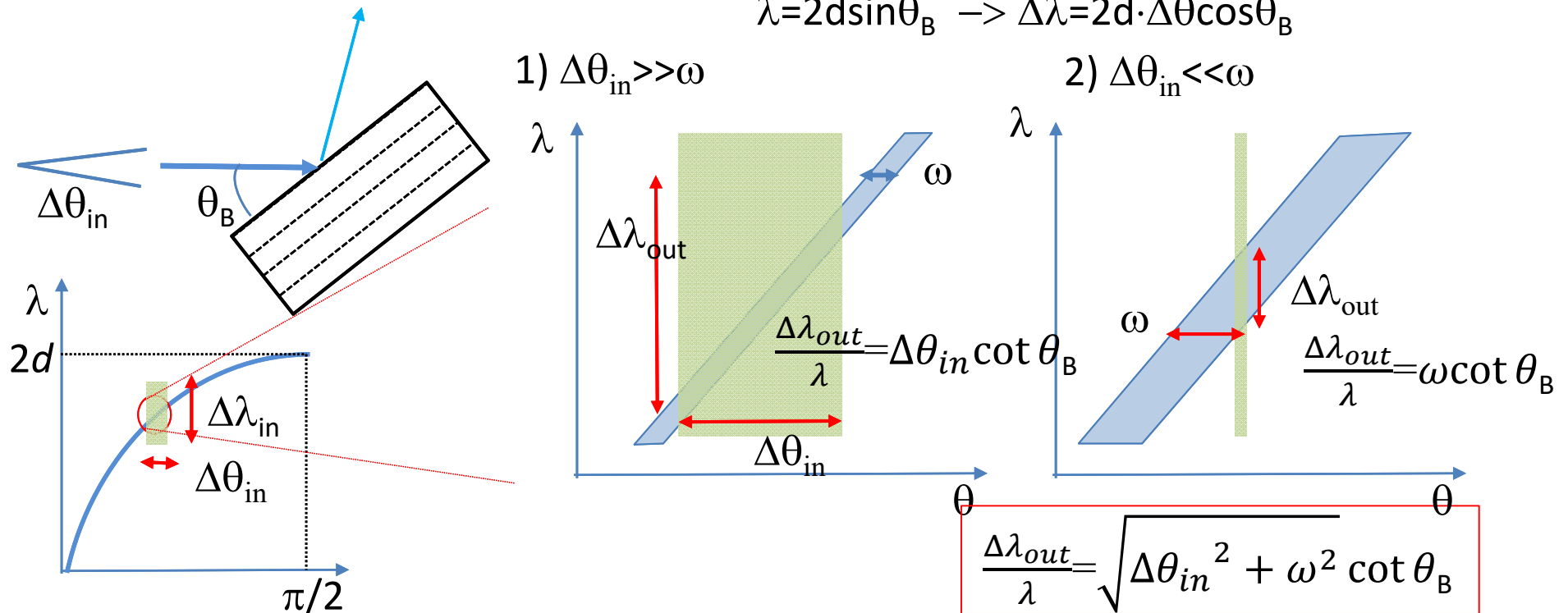
**Dynamical theory of diffraction:** Multiple reflections in perfect crystal gives finite angular width (**Darwin width**) for total external reflection

A. Authier, “Dynamical Theory of X-ray Diffraction” Oxford Univ. Press (2001)

J.W.M. DuMond, Phys. Rev. **32** (1937) 872

# Monochromator on DuMond diagram

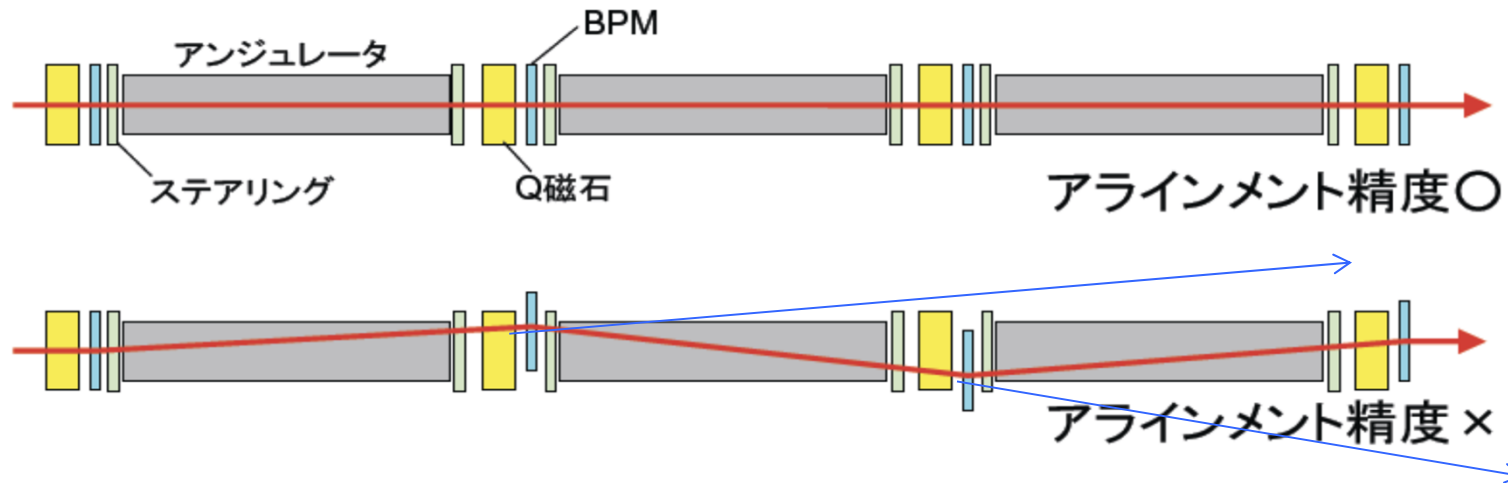
$$\lambda = 2d \sin \theta_B \rightarrow \Delta \lambda = 2d \cdot \Delta \theta \cos \theta_B$$



Typical parameters with silicon (111) monochromator

|                     | Incident resolution $(\Delta \lambda / \lambda)_{in}$ | Incident divergence $\Delta \theta_{in}$ | Darwin width $\omega$   | Output resolution $(\Delta \lambda / \lambda)_{out}$ |
|---------------------|---|--|---|--|
| Bending magnet      | $\sim 1$  | $\sim 100$ urad                          |   | $\sim 1e-3$  |
| Undulator radiation | $\sim 1e-2$   | $\sim 10$ urad                           | $\sim 20$ urad w Si (111)<br>@ $\lambda = 1 \text{ \AA}$ ( $\theta_B = 9.1^\circ$ ) | $\sim 1e-4$  |
| XFEL                | $\sim 1e-3$   | $\sim 1$ urad                            |   | $\sim 1e-4$  |

# Application of monochromator: Precise ID tuning



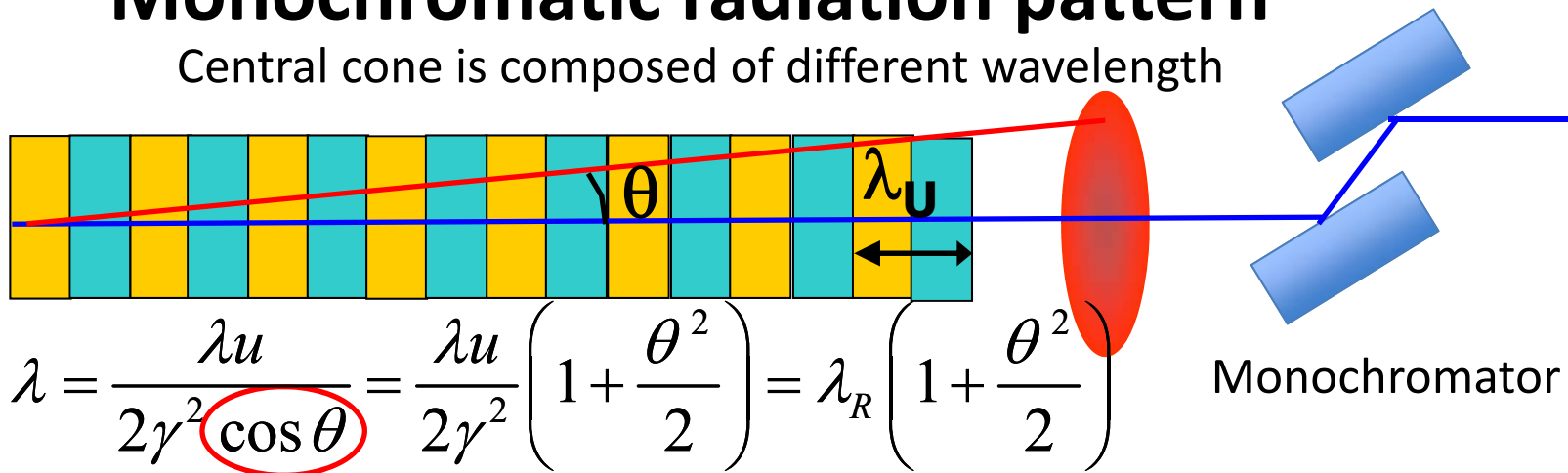
- For efficient lasing, overlap between e-beam and p-beam with an accuracy of  $\sim \text{urad}$  is required
- E-beam trajectory easily bends at the edges of undulator modules
- P-beam goes through along the e-beam in the undulator
- P-beam can be used to monitor the e-beam trajectory in each undulator module

Cf. central cone of the undulator radiation

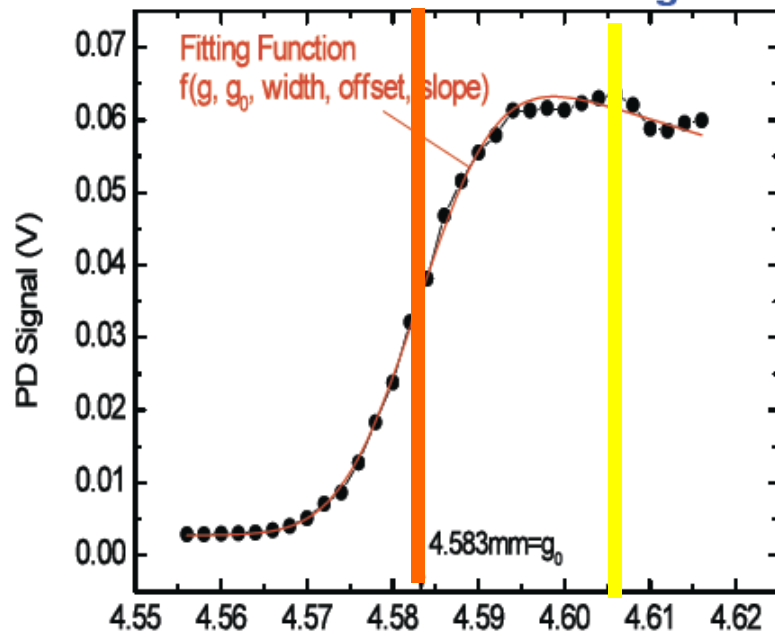
$$1/g = 1/16000 = 60 \text{ urad for } 8 \text{ GeV} \rightarrow \text{too large}$$

# Monochromatic radiation pattern

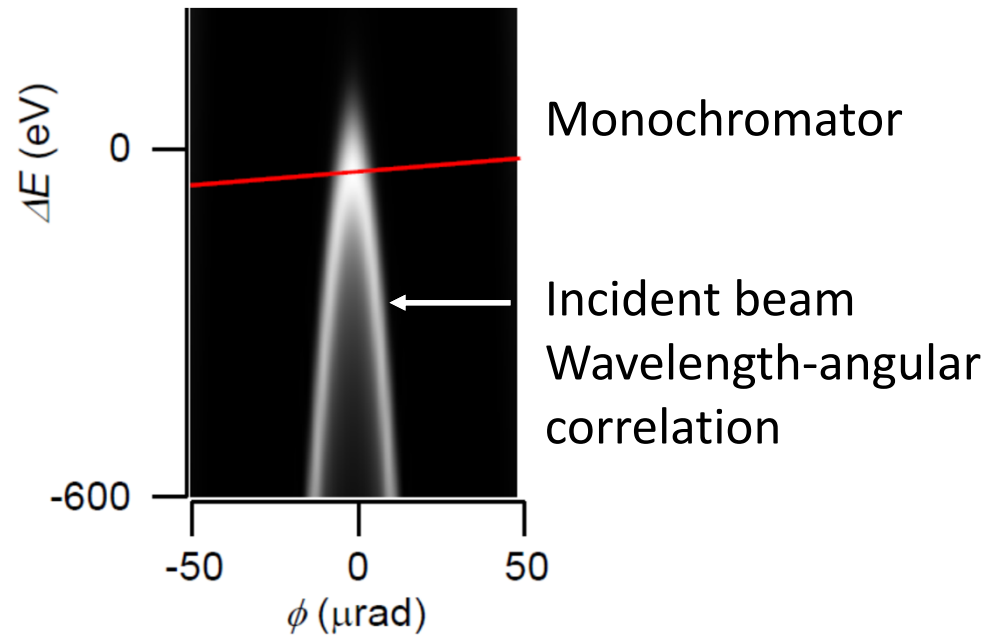
Central cone is composed of different wavelength



## Precise K-value Tuning



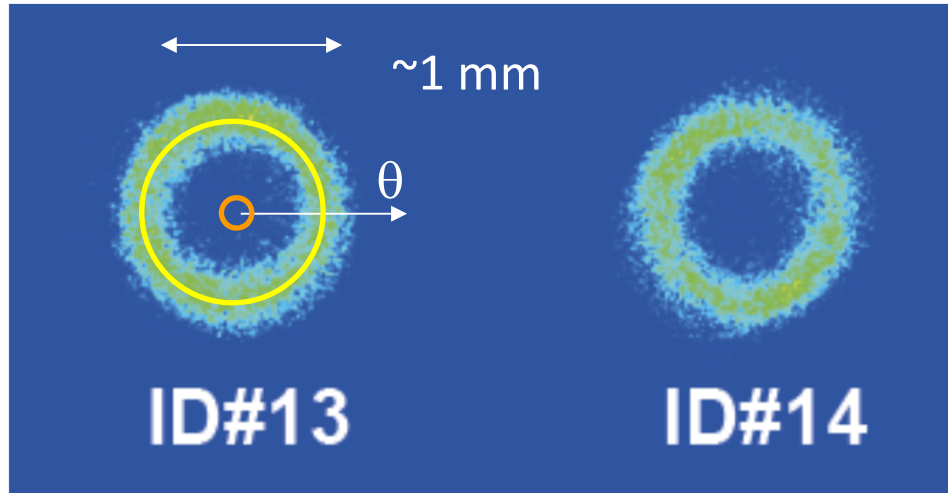
Wavelength





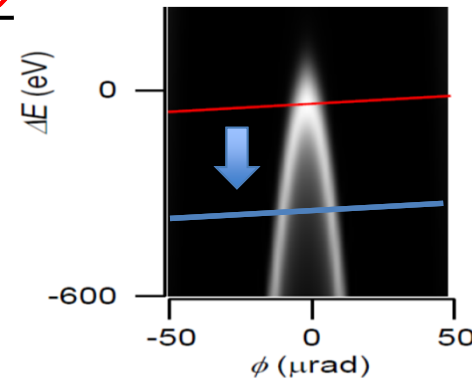
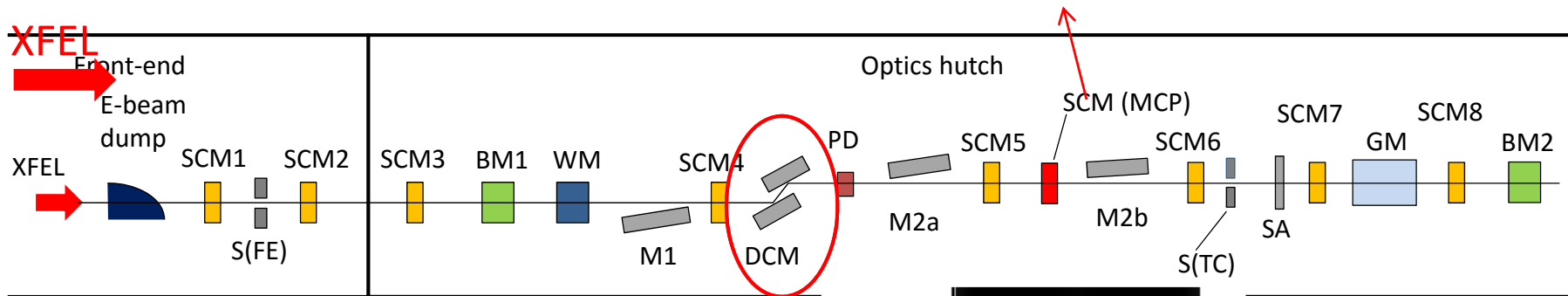
# X-ray based undulator alignment

Profile of **monochromatized** spontaneous radiation



Angular diameter:  $\sim 10$   $\mu\text{rad}$   
Centroid: 1  $\mu\text{rad}$

High-sensitivity screen  
monitor for spontaneous x-ray  
detection

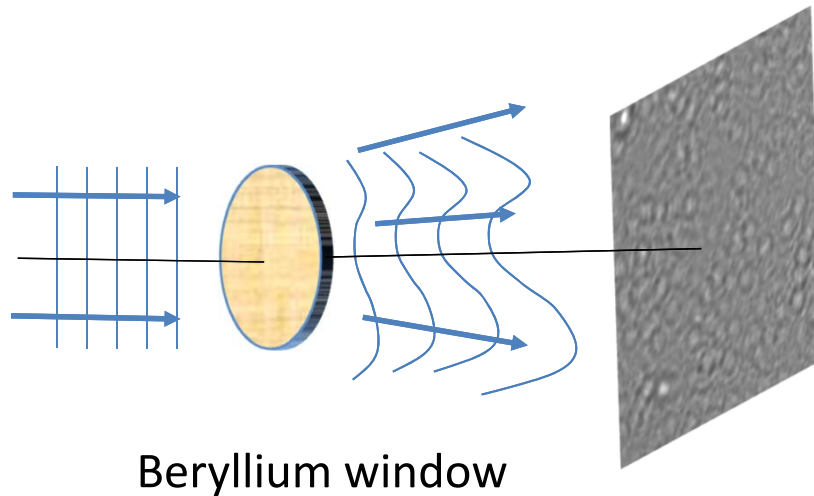


T. Takashi et al., Phys. Rev. ST-AB  
15 (2012) 110701

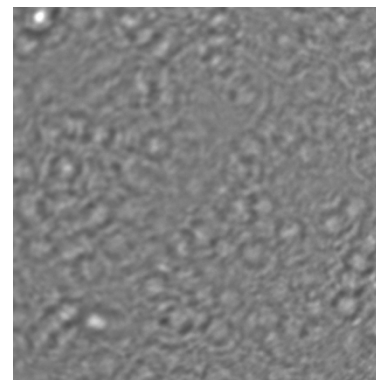
# Function (III): Speckle-free X-ray optics for transversely coherent sources

Coherent illumination on imperfect optical elements can easily produce speckles

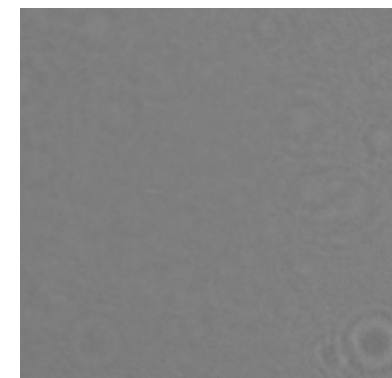
Measured at 1-km BL of SPring-8



Yabashi et al., J Synchrotron Rad.  
21 (2014) 976



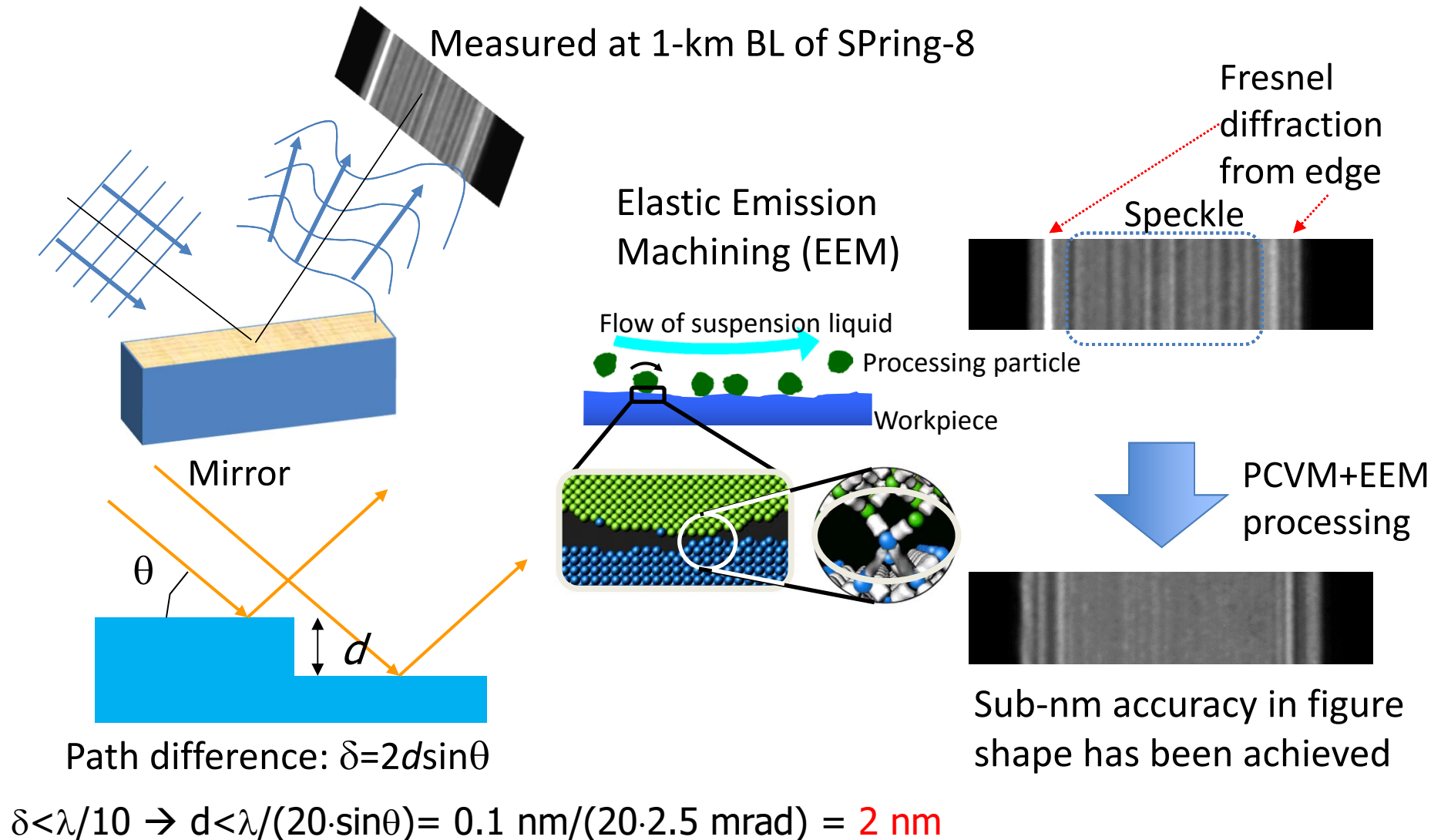
IF1 grade Be



PVD Be

# Function (III): Speckle-free X-ray optics for transversely coherent sources

Coherent illumination on imperfect optical elements can easily produce speckles



# Short summary

- Reflective/refractive/diffractive optics are used for controlling x-ray properties of beam size (focusing) or bandwidth (monochromator)
- Special high quality is required for x-ray optics under coherent x-ray illumination to avoid speckles

## References:

- J. Als-Nielsen & D. McMorrow, “Elements of Modern X-ray Physics” (Wiley, 2001): General introduction of x-ray optics and x-ray applications
- A. Authier, “Dynamical Theory of X-ray Diffraction” Oxford Univ. Press (2001): An authentic textbook on dynamical theory of diffraction
- Yabashi et al., J Synchrotron Rad. **21** (2014) 976; Overview of recent development of x-ray optics for coherent x-ray applications

# Contents

1. Introduction: Brief history of photon beamlines for SR/XFEL
2. Preparatory: Phase space
3. X-ray optics
- 4. X-ray diagnostics**
  1. Pulse energy
  2. Pulse duration
  3. Arrival timing
5. Design of beamline
6. Summary

# X-ray diagnostics

Characterization of x-ray beam properties in **6-dimensional phase space** (+ polarization) + coherence

- **Total intensity**

- **Transverse x 4**

Real space:  $(x,y)$  ← fluorescent screens

Angular direction:  $(\theta_x, \theta_y)$

←  $L \times \theta$ : free-space propagation + size measurement

- **Longitudinal x 2**

Frequency (=photon energy or wavelength)  $h\nu$

Time: **pulse duration  $t$**

*+ arrival timing  $\tau$  for pump-probe*

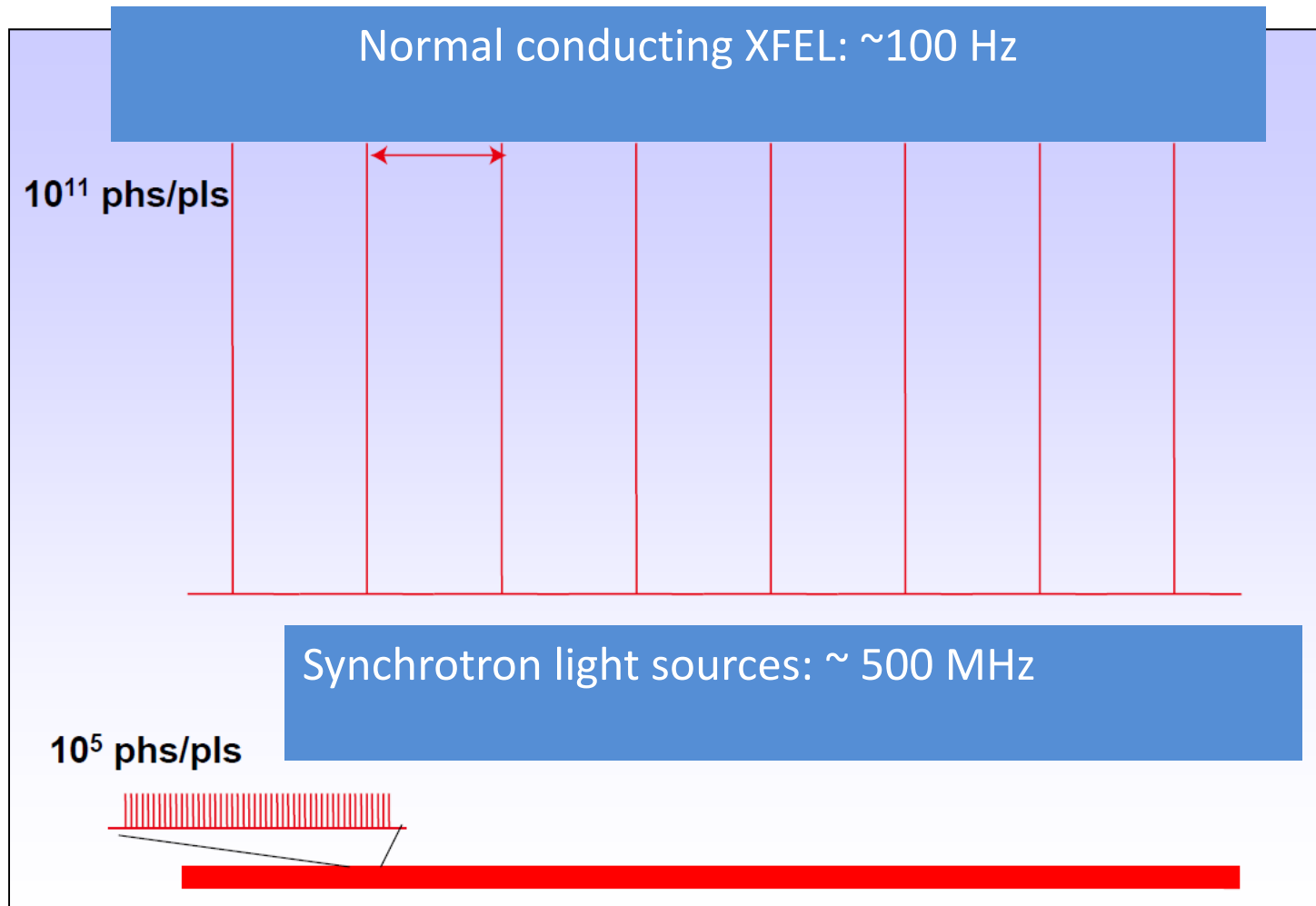
*experiments with external optical laser*

- **Coherence**

# Key words

- Absolute or relative ?
- Resolution and range ?
- How fast ?
  - XFEL: Shot-to-shot fluctuation
  - Shot-to-shot measurements are desirable
- Destructive or nondestructive ?
  - Destructive: full photons are available for diagnostics, more accurate measurements
  - Nondestructive: diagnostics parallel to experiments

# Temporal structure

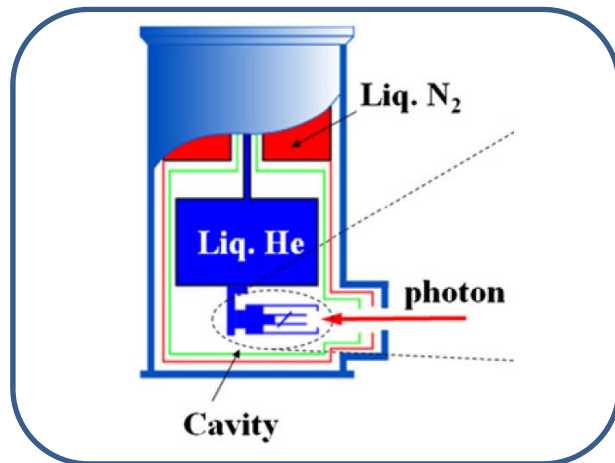




# Pulse energy measurement (I)

- Pulse energy is the most fundamental parameter for both machine and experimental sides
- Pulsed nature → signals easily saturated; reliable measurement is challenging

## Cryogenic radiometer

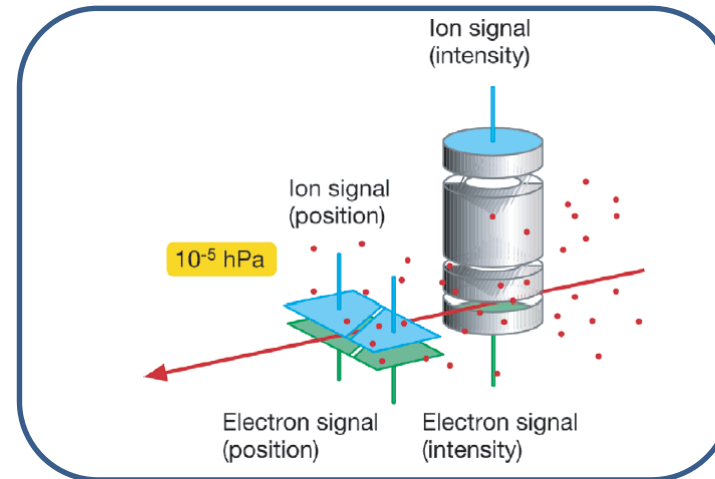


Detection of small temperature increment after x-ray absorption

**Destructive**  
**Portable**

T. Tanaka et al., *Nucl. Instrum. Methods A* 659, 528 (2011).

## XGMD: Gas monitor detector (DESY, PTB)



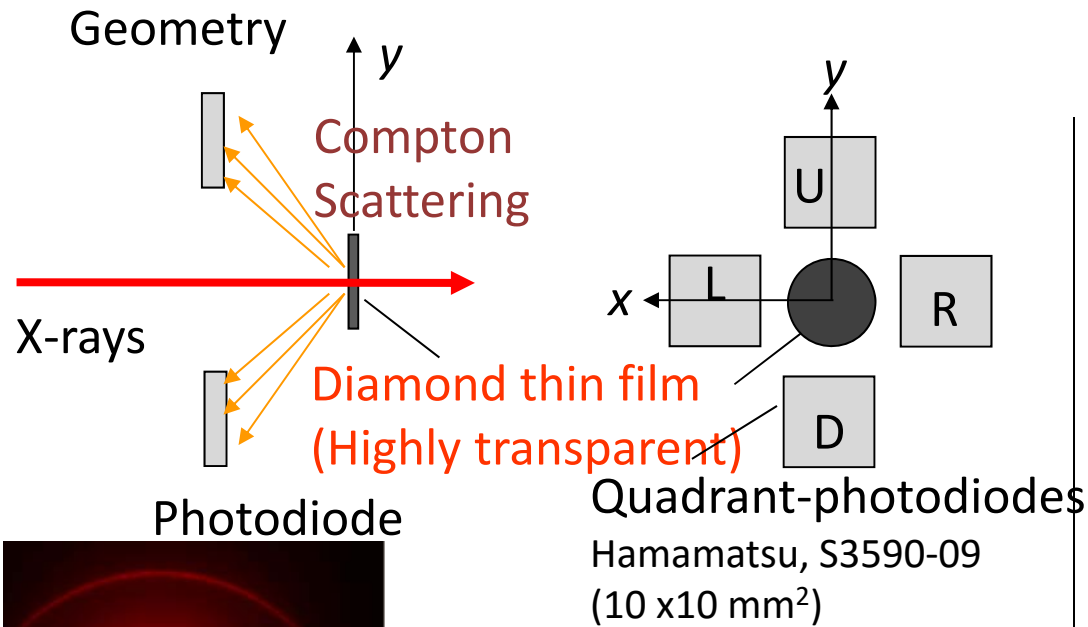
Detection of electrons/ions ionized with x-ray irradiation

**Nondestructive**  
**Vacuum system**

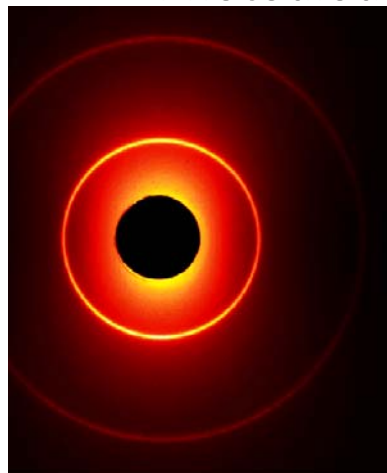
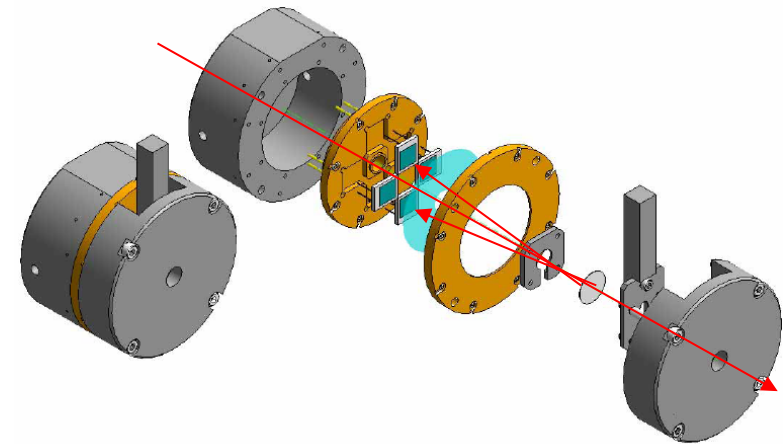
M. Richter et al, *Appl. Phys. Lett.* **83** 2970 (2003)  
K. Tiedtke et al, *J. Appl. Phys.* **103** 094511 (2008)

# Total intensity measurement (II)

Detection of x-ray scattering (mainly Compton scattering) from thin foil



K. Tono et al. *RSI* 82, 023108 (2011)



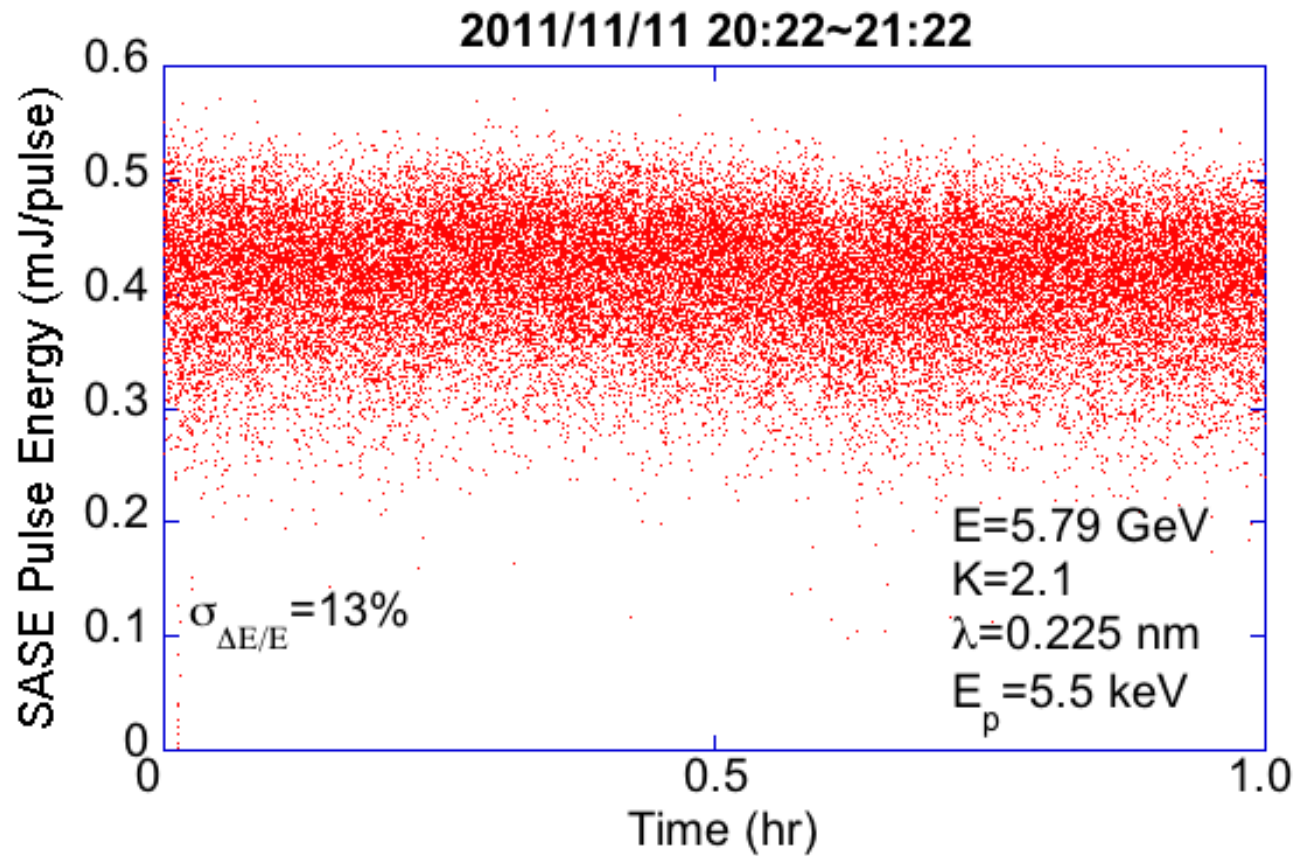
$$\propto (I_L + I_R + I_U + I_D)$$

Position  
(center  
of mass)

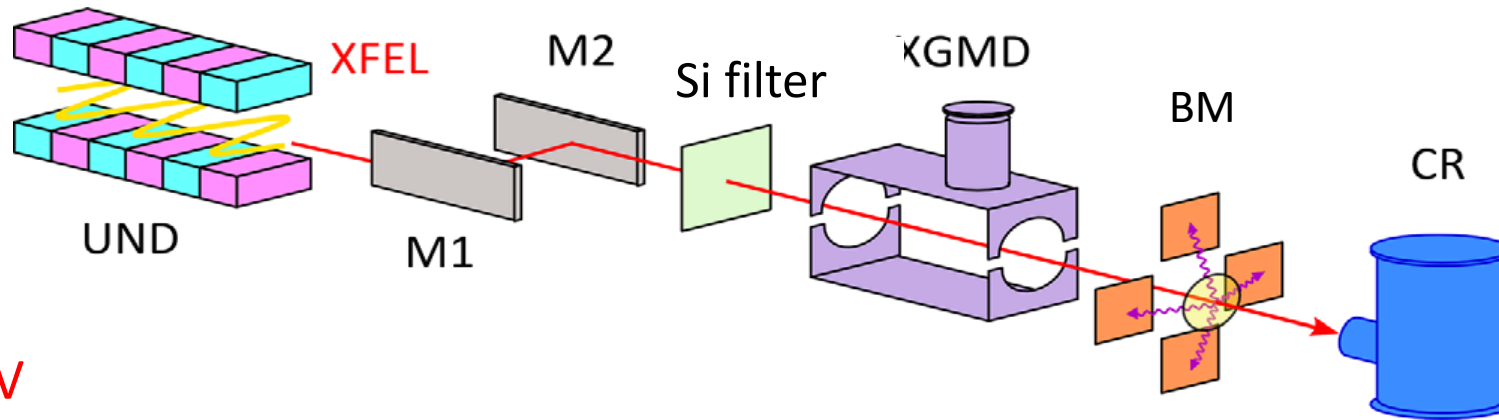
$$x = K_x \frac{I_L - I_R}{I_L + I_R} = K_x \Delta I_x$$

$$y = K_y \frac{I_U - I_D}{I_U + I_D} = K_y \Delta I_y$$

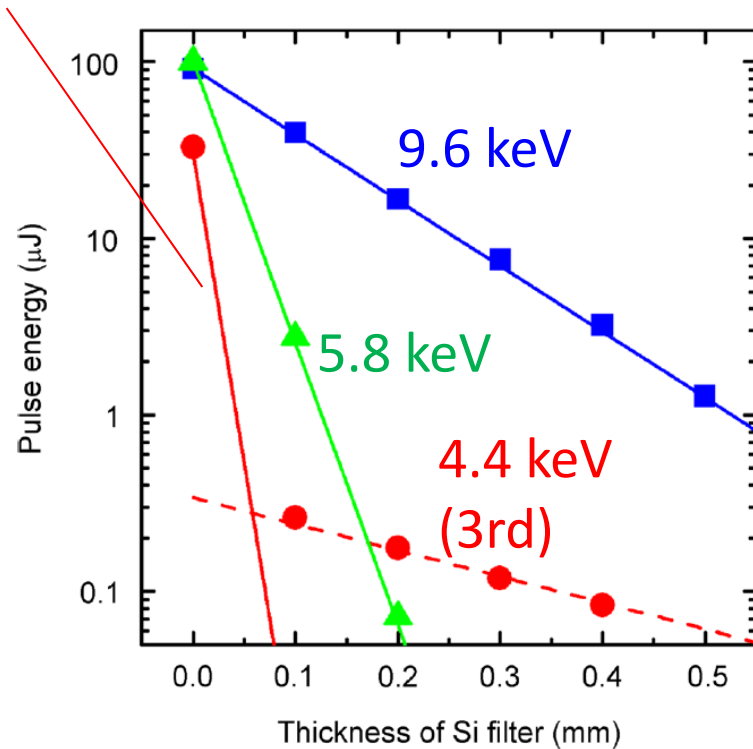
# Shot-by-shot measurement



# Mutual Calibration



4.4 keV  
(fundamental)



| Photon energy / keV | Pulse energy / $\mu\text{J}$ |                 |
|---------------------|------------------------------|-----------------|
|                     | Radiometer                   | XGMD            |
| 4.4                 | $32.26 \pm 0.35$             | $32.9 \pm 2.0$  |
| 5.8                 | $104.2 \pm 1.3$              | $106.6 \pm 6.1$ |
| 9.6                 | $95.3 \pm 2.3$               | $93.9 \pm 6.1$  |
| 13.6                | $42.2 \pm 1.1$               | $40.8 \pm 2.9$  |
| 16.8                | $0.96 \pm 0.03$              | ---             |
|                     | AIST (JPN)                   | PTB             |

*Excellent agreement*

# Contents

1. Introduction: Brief history of photon beamlines for SR/XFEL
2. Preparatory: Phase space
3. X-ray optics
- 4. X-ray diagnostics**
  1. Total intensity
  - 2. Pulse duration**
  3. Arrival timing
5. Design of beamline
6. Summary

# Pulse duration measurement

Deflection cavity after undulator:  
Measure time-resolved energy  
loss/spread after x-ray lasing

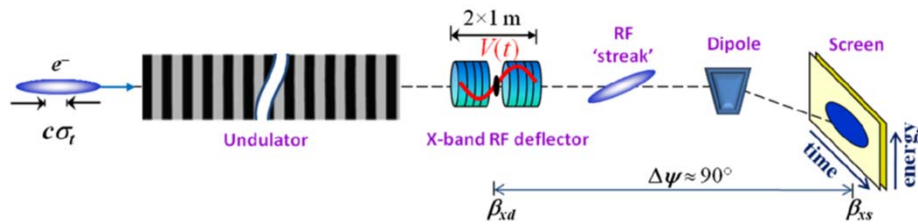


FIG. 1. A layout of the diagnostic system with a transverse rf deflector and an energy spectrometer.

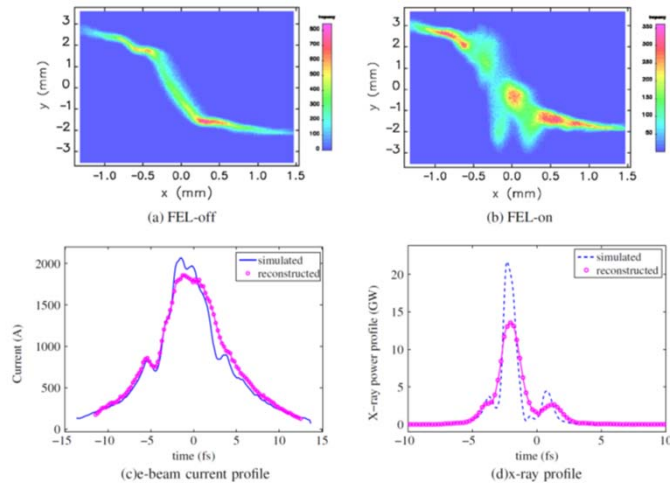
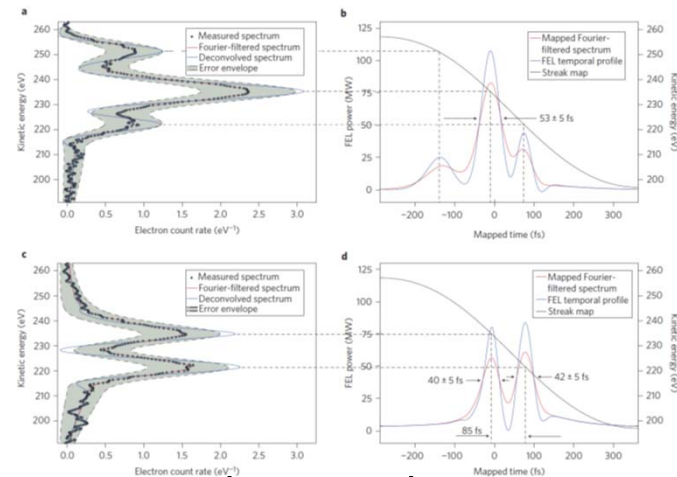
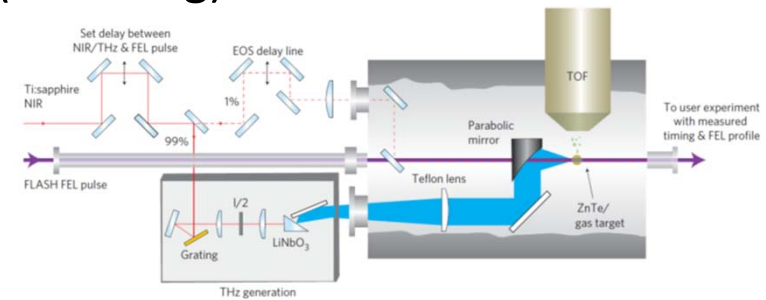


FIG. 4. The simulated images on the screen representing e-beam longitudinal phase space for FEL-off (a) and FEL-on (b). The bunch size is 100 pC with an energy spread of 1%. Parts (c) and (d) show the reconstructed e-beam current and FEL x-ray profiles (magenta) with the simulated profiles (blue). The bunch head is to the left.

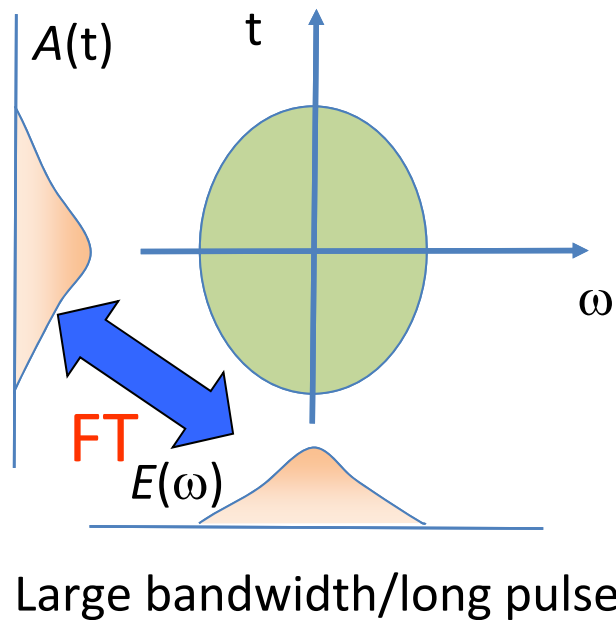
XTCV@LCLS  
Ding et al., PRST **14**, 120701 (2011)

THz streaking method:  
photoelectrons -> modulation of  
energy with external THz field  
(streaking)



Grguras et al., Nat. Photon **6**, 852 (2012)  
Fruhling et al., Nat. Photon **3**, 523 (2009)

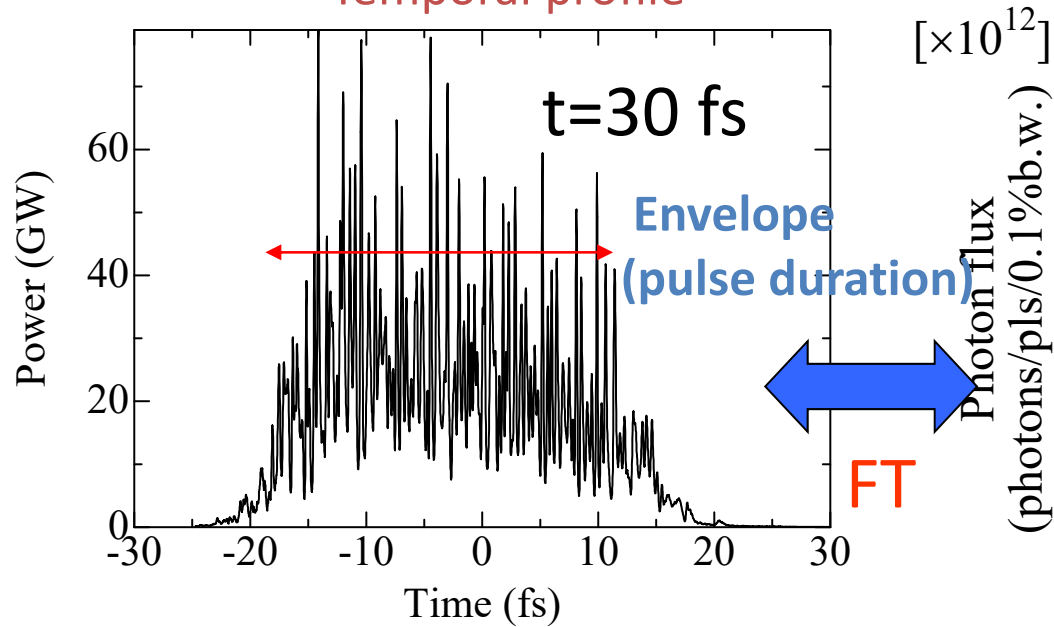
# Distribution in longitudinal phase space



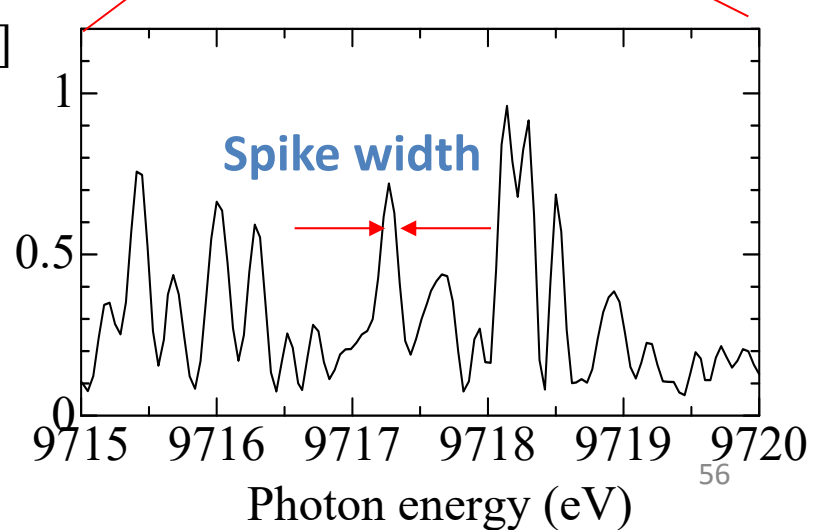
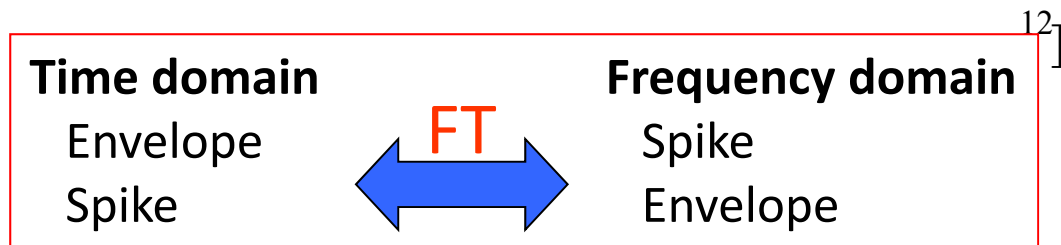
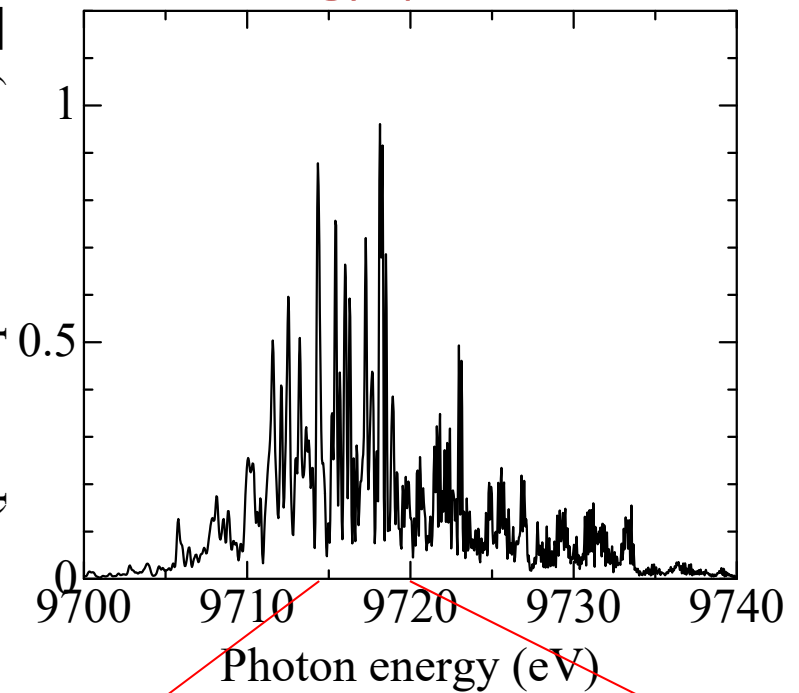
- Distribution in frequency domain  $E(\omega)$   $\leftarrow$  FT  $\rightarrow$  Distribution in temporal domain  $A(\theta)$

# Simulation for SASE-FEL (I): Longer pulse

Temporal profile



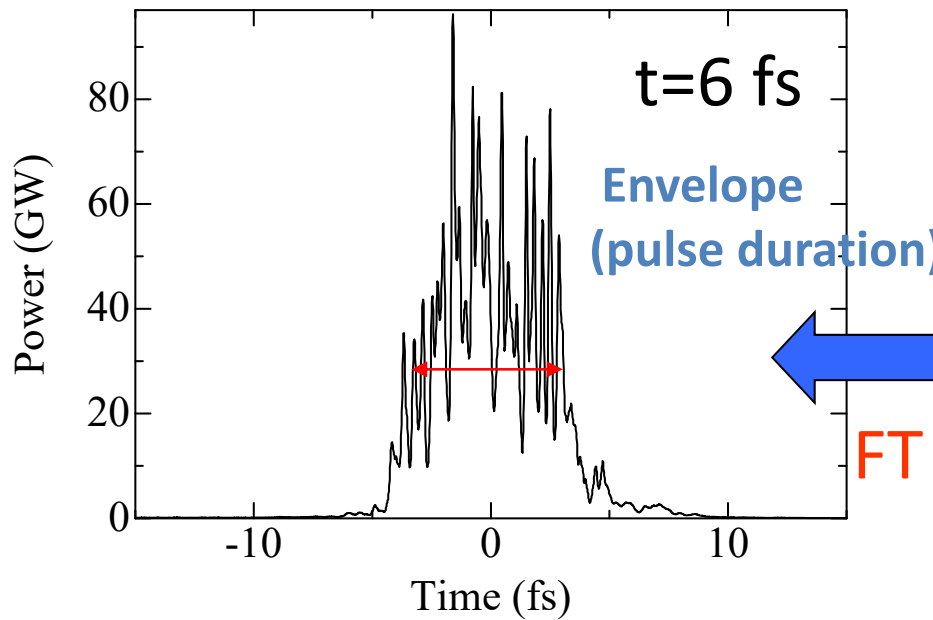
Energy spectrum



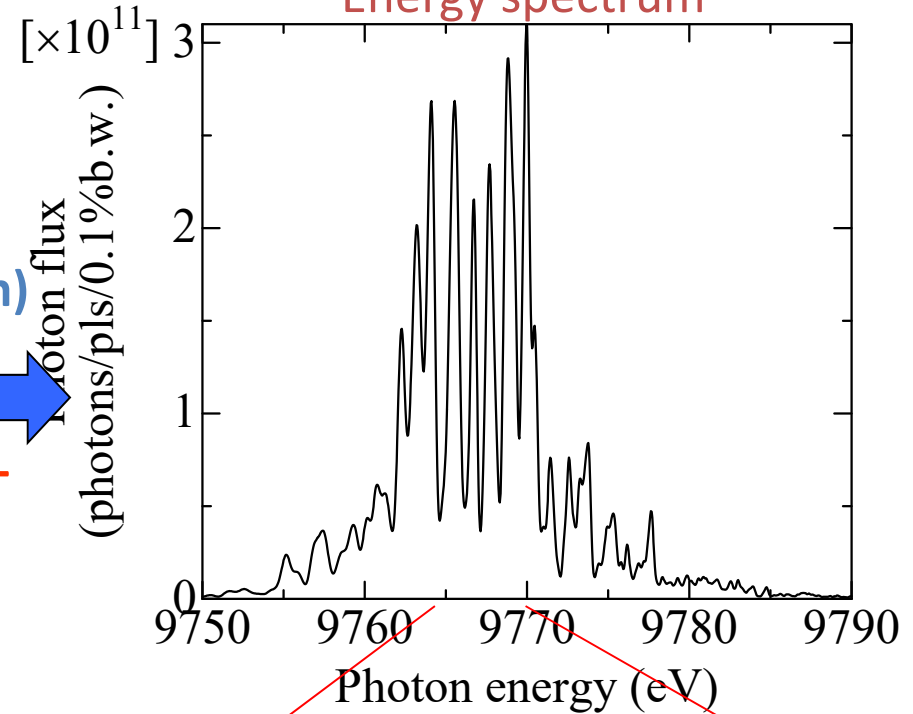


# Simulation for SASE-FEL (II): Shorter pulse

Temporal profile



Energy spectrum



**Pulse duration**

Shorter  
Longer



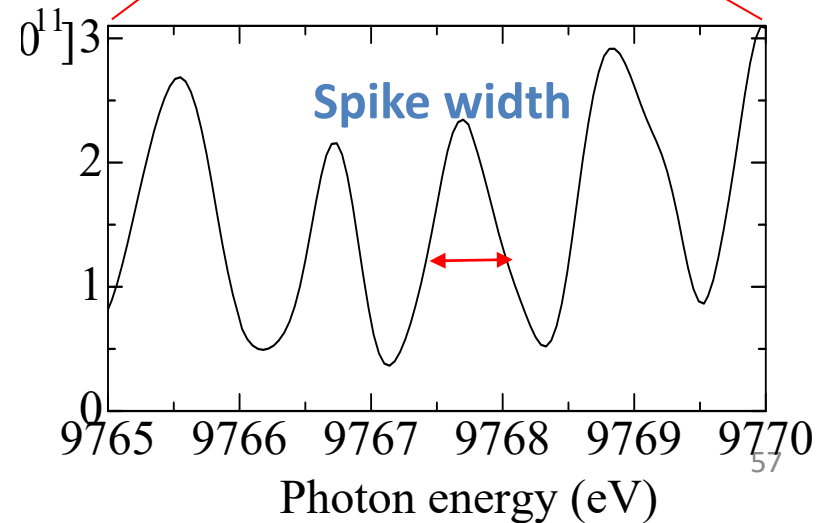
**Spike width**

Wider  
Narrower

Measurement of energy spike  
(high resolution)



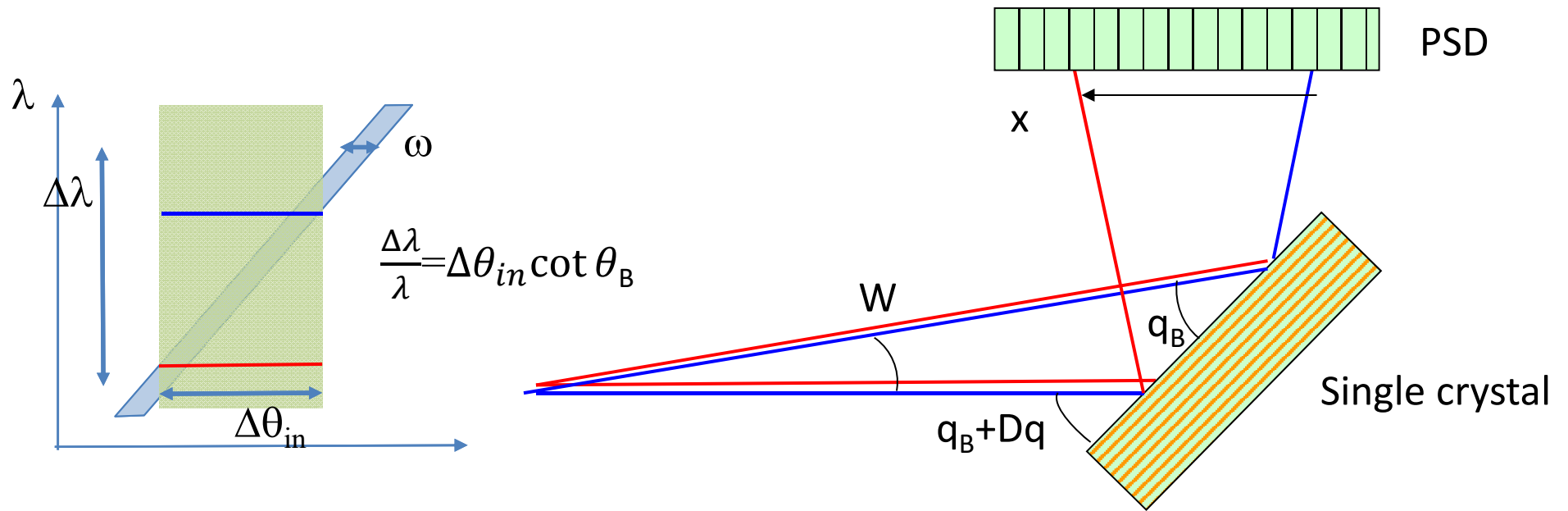
Evaluation of pulse duration



# Measurement with perfect-crystal spectrometer

Divergent beam + flat crystal analyzer

Single-shot detection



$$\frac{\Delta\lambda}{\lambda} = \frac{\Delta E}{E} = \Delta\theta \cot \theta_B$$

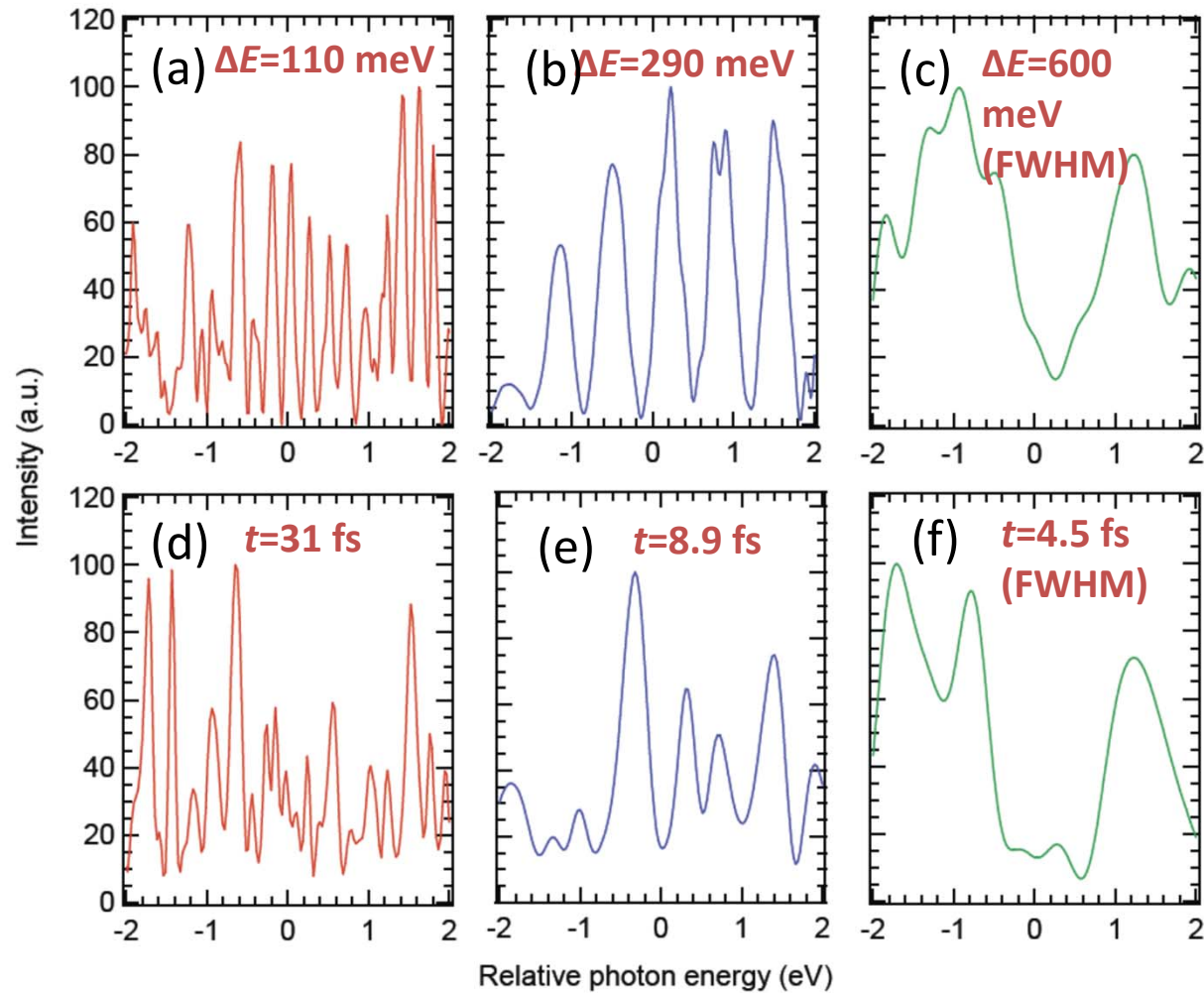
Energy Angle

$$\xi = L\Delta\theta = \frac{\Delta E}{E} L \tan \theta_B$$

Position

# Example

Measurement  
at SACLA



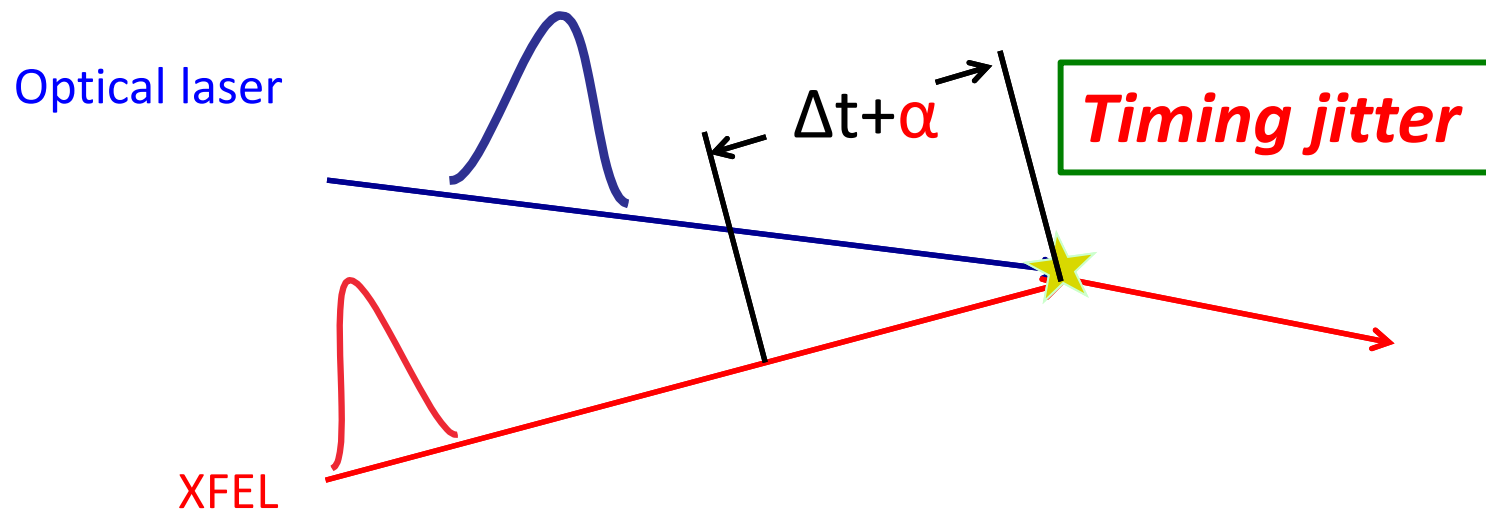
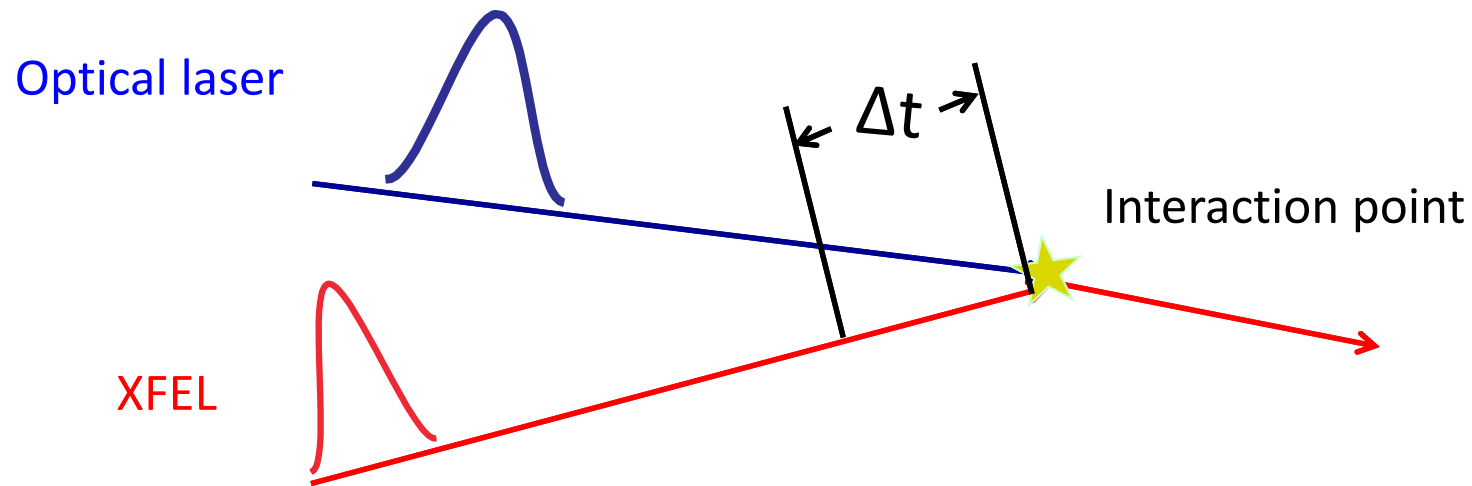
FEL simulation  
(SIMPLEX by  
Takashi Tanaka)

Y. Inubushi *et al.*, *Phys. Rev. Lett.* **109**, 144801 (2012).

# Contents

1. Introduction: Brief history of photon beamlines for SR/XFEL
2. Preparatory: Phase space
3. X-ray optics
- 4. X-ray diagnostics**
  1. Total intensity
  2. Pulse duration
  - 3. Arrival timing**
5. Design of beamline
6. Summary

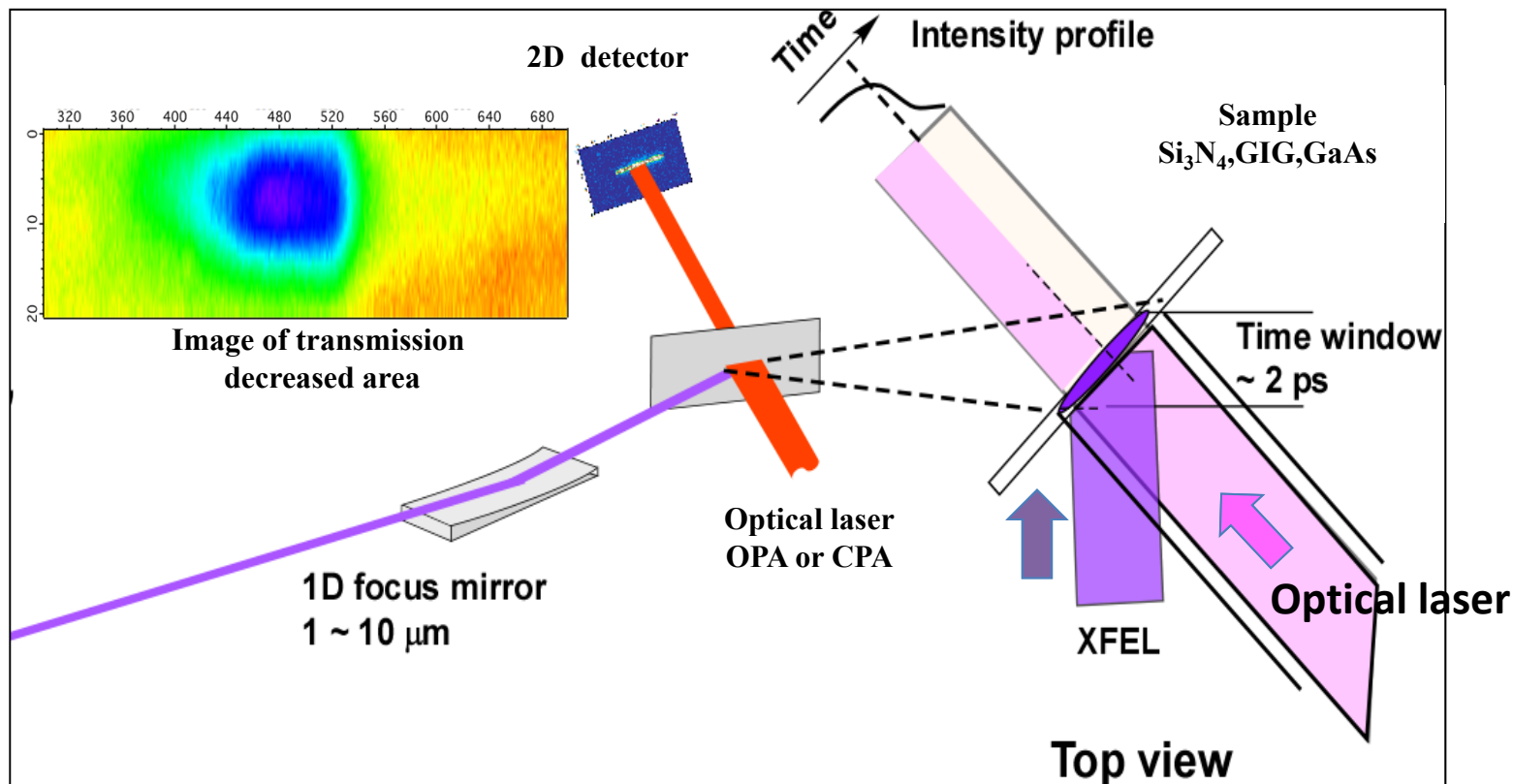
# Arrival timing



Measure timing jitter for every pulse → Sorting with “tag” information

# Arrival timing measurement

XFEL excites electronic system in fs scale → probed by change of optical transmittance  
Spatial encoding technique: cross-beam geometry between XFEL and optical laser

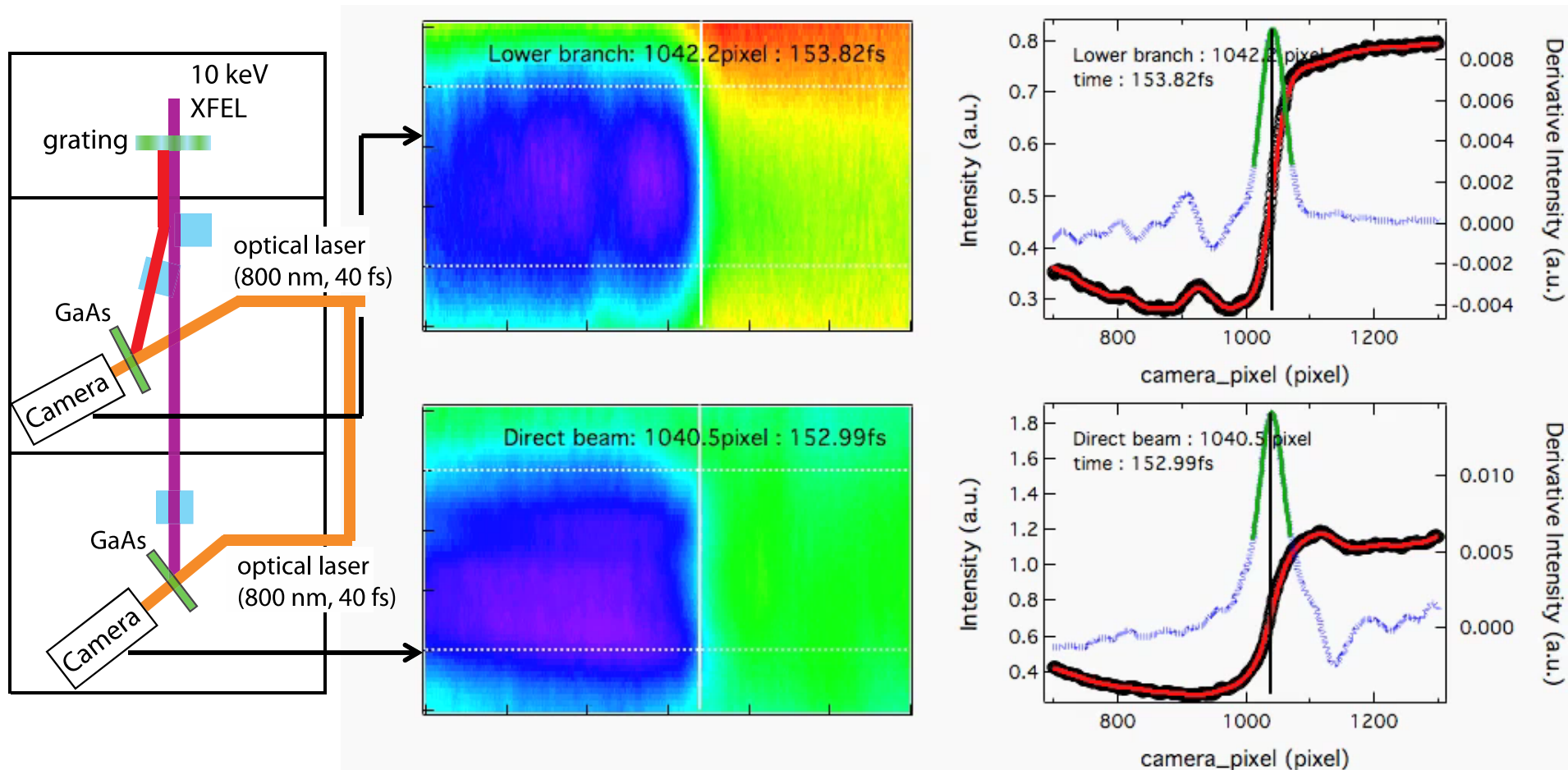


Harmand et al., Nature Photon **7** 215 2012

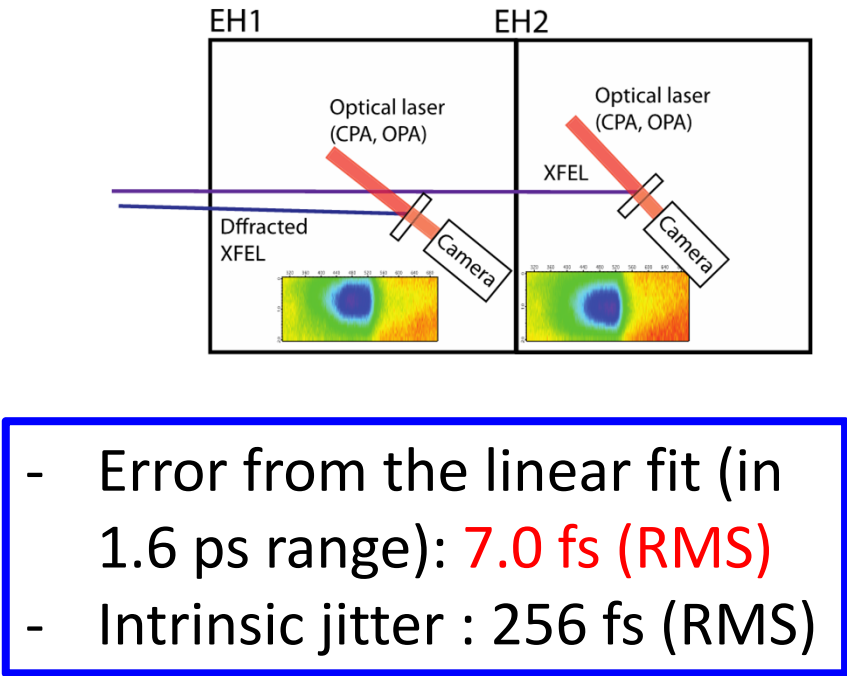
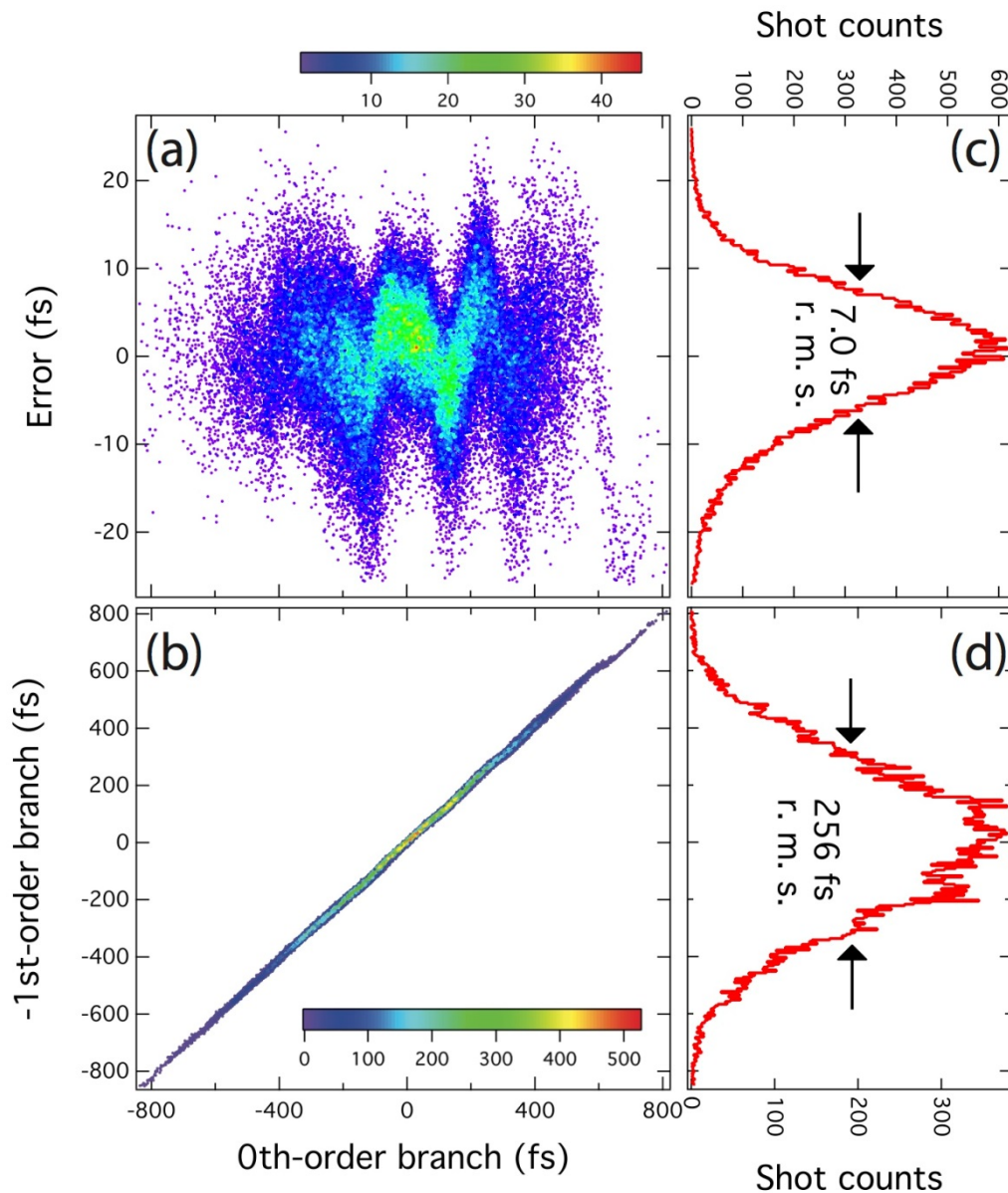
Gahl et al., Nature Photon **2** 165 2008

T. Sato et al APEX **8**, 012702 (2015)

# Correlation measurement between two independent setup



# Correlation between independent measurements



- Error from the linear fit (in 1.6 ps range): **7.0 fs (RMS)**
- Intrinsic jitter : **256 fs (RMS)**



# Short summary

- New developments are on-going for characterizing XFEL beam properties, especially towards achieving high resolution
- Cross-check among different schemes is important for assuring reliability

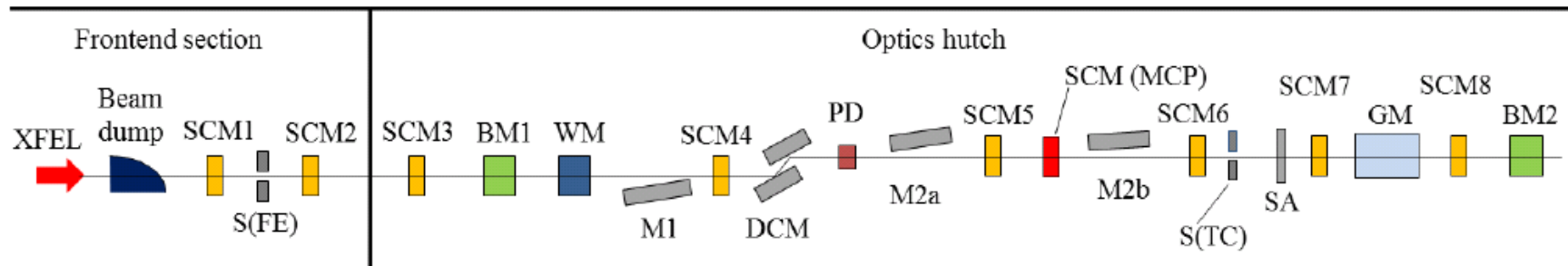
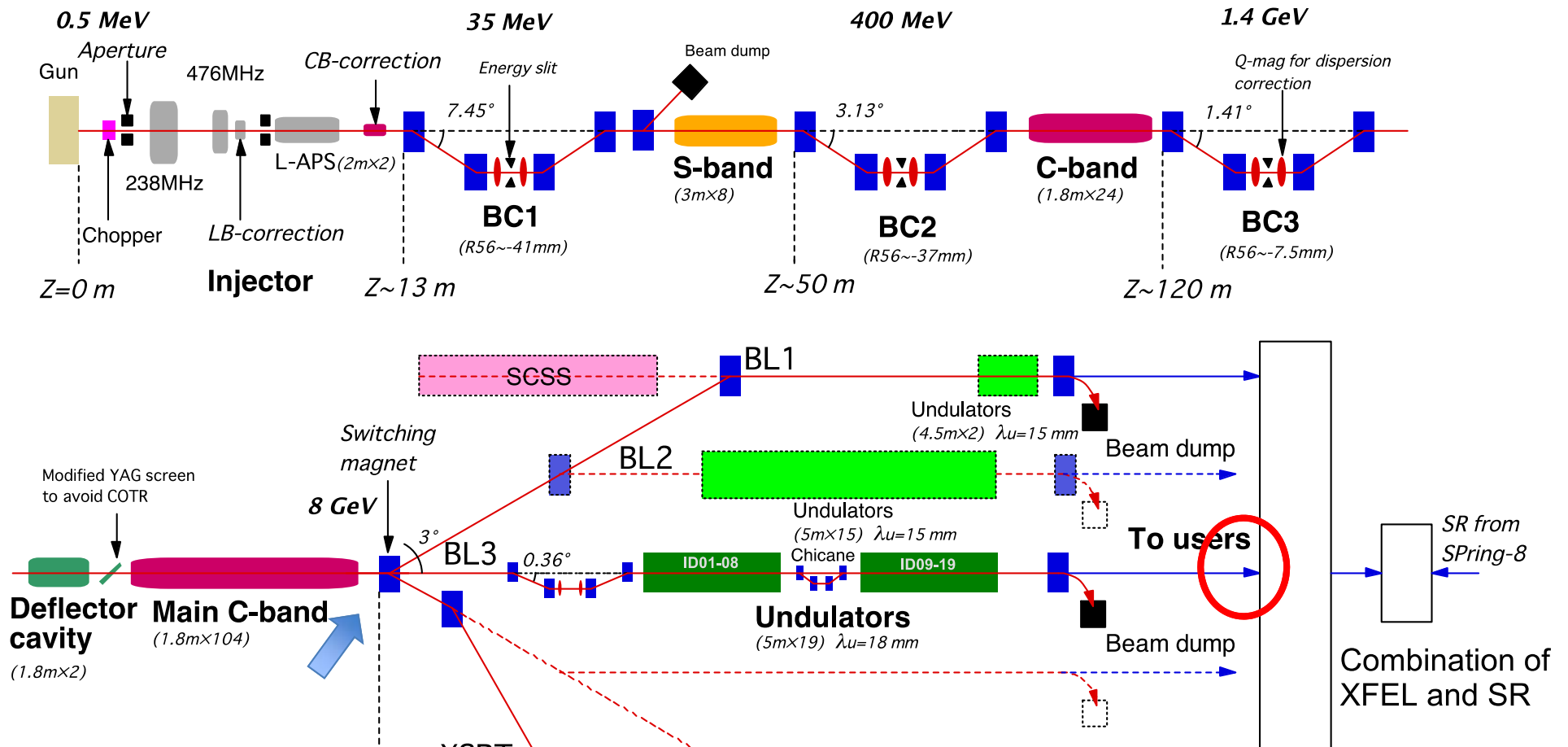
## References:

- K. Tono et al., New Journal Phys. **15** (2013) 083035: Review of x-ray beamline and diagnostics of SACLA
- Harmand et al., Nature Photon **7** (2012) 215: Arrival timing monitor at LCLS

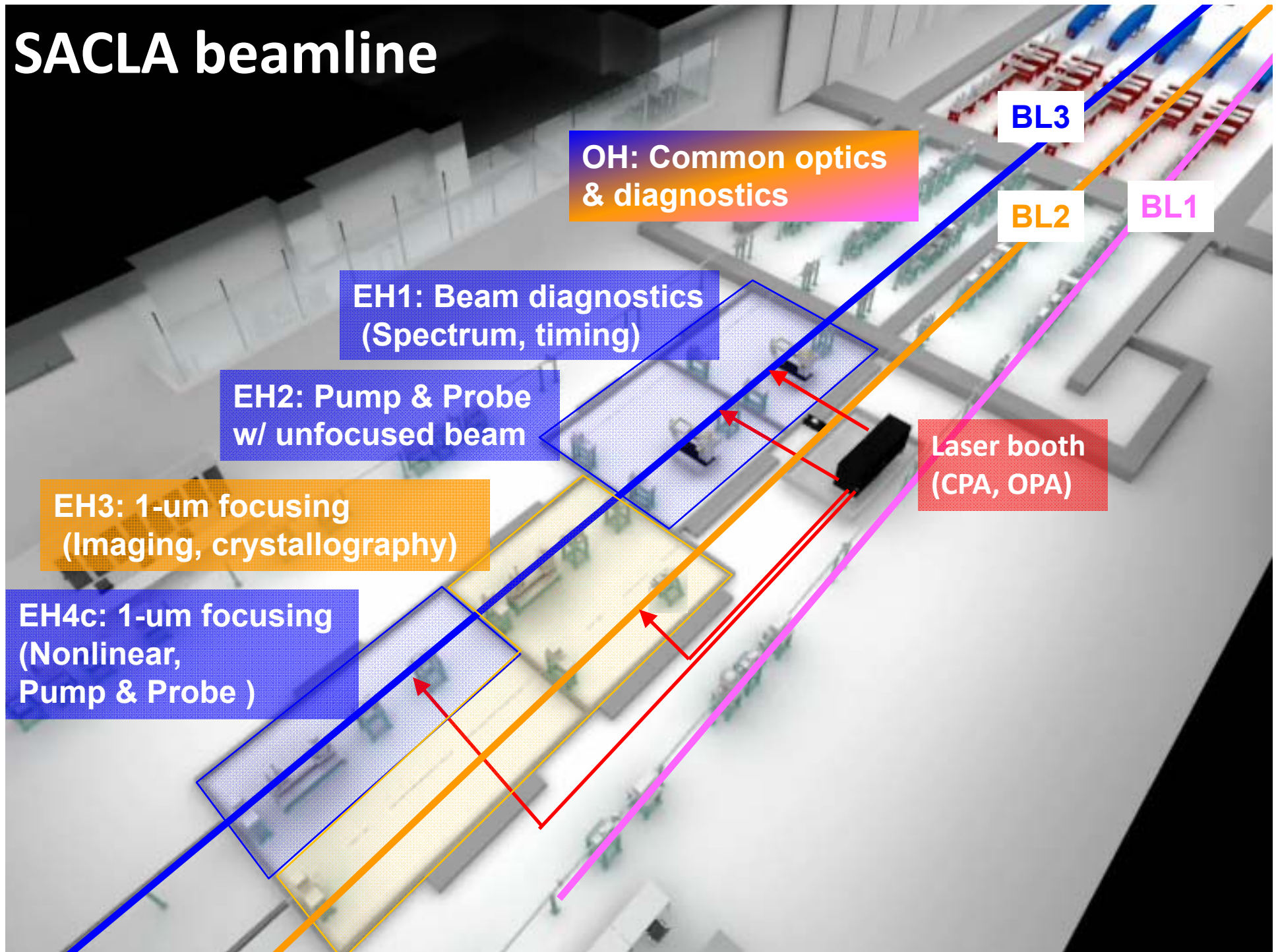
# Contents

1. Introduction: Brief history of photon beamlines for SR/XFEL
2. Preparatory: Phase space
3. X-ray optics
4. X-ray diagnostics
5. Design of XFEL beamline  
Example: SACLA  
[K. Tono et al., New Journal Phys. 15 \(2013\) 083035](#)
6. Summary

# Example: SACLA

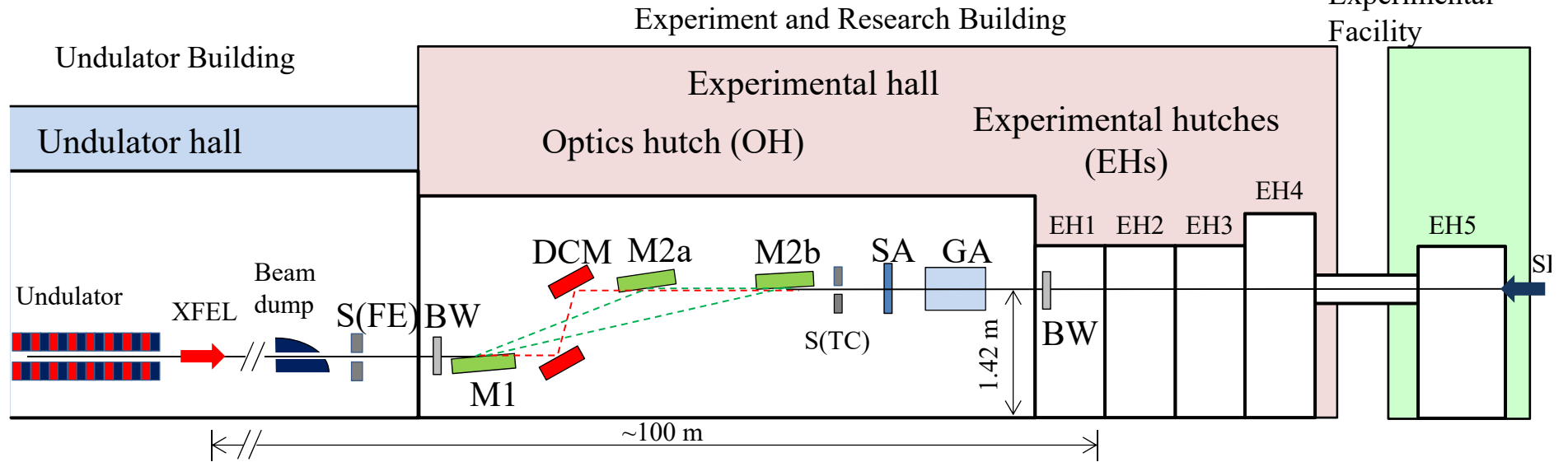


# SACLA beamline



# Configuration of beamline & optics at SACLA

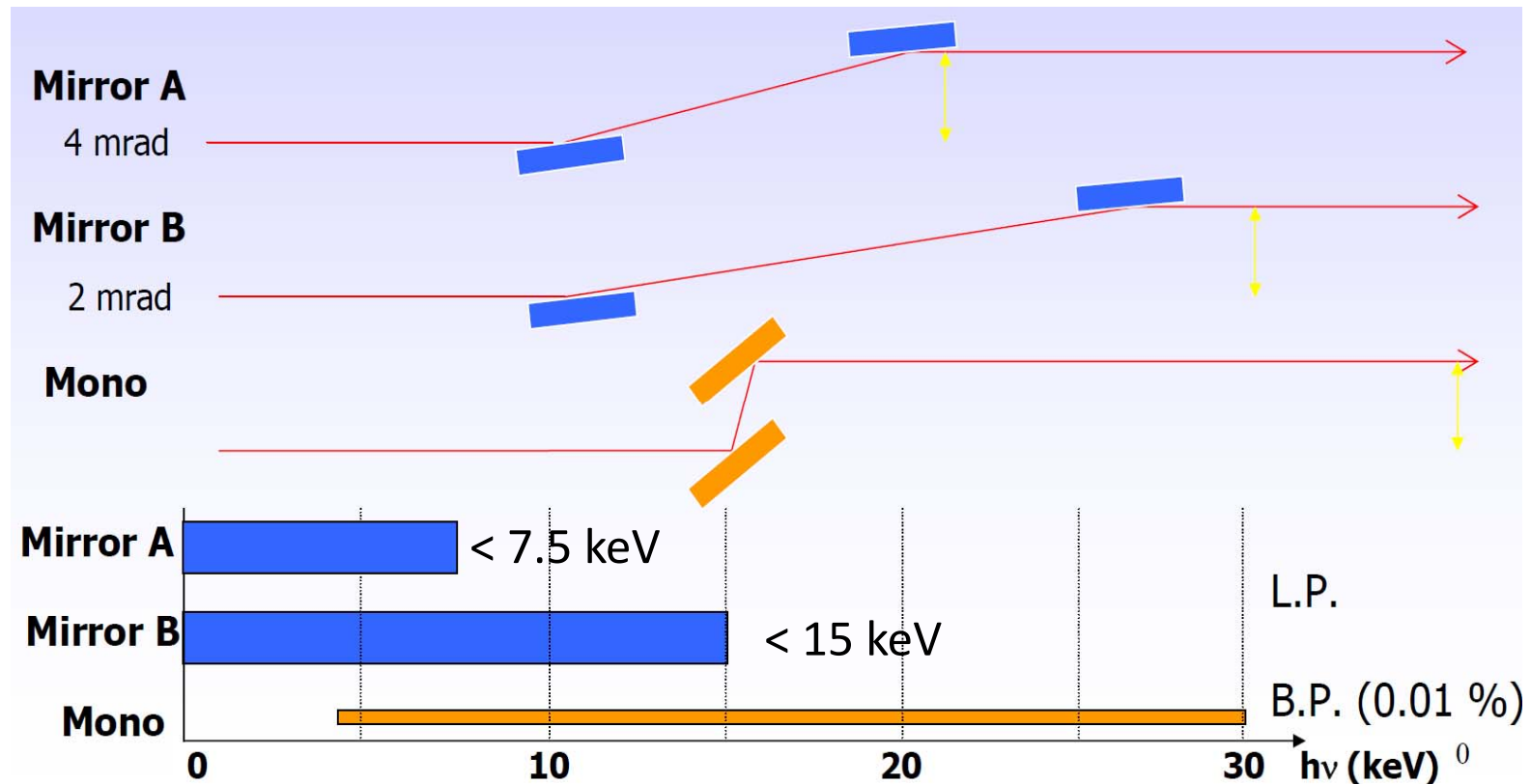
SACLA-Spring-8  
Experimental Facility



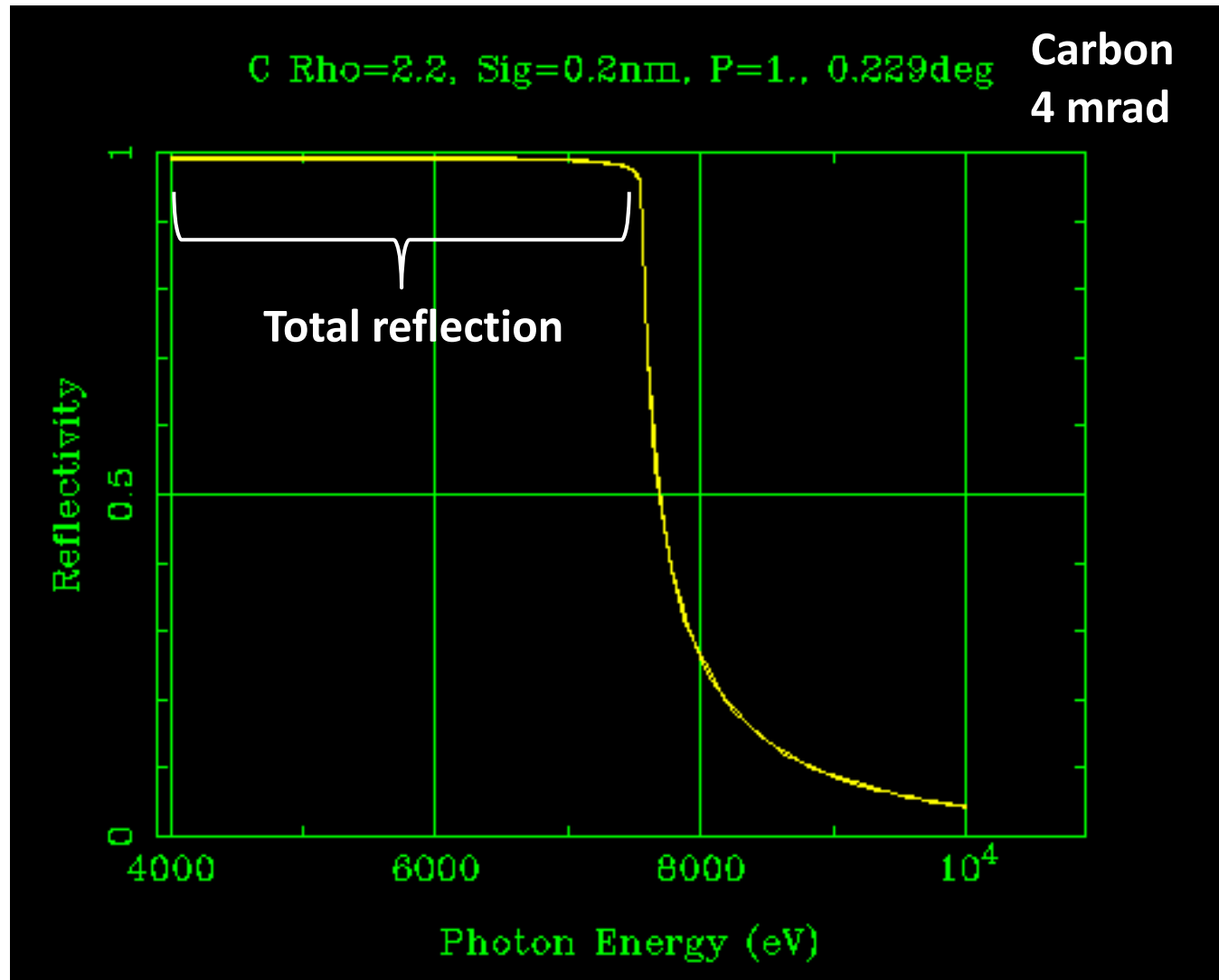
|              | Name                         | Function                                   |
|--------------|------------------------------|--|
| S(FE)        | Frontend slit                | Filtering (spatial)                        |
| BW           | Be optical window            | Vacuum protection<br>Filtering (high pass) |
| M1, M2a, M2b | Plane mirrors                | Filtering (low pass)                       |
| DCM          | Double crystal monochromator | Filtering (band pass)                      |
| S(TC)        | 4-way slit                   | Filtering (spatial)                        |
| SA           | Solid attenuator             | Attenuation                                |
| GA           | Gas attenuator               | Attenuation                                |

# Basic optics

- Plane mirrors (A & B): rejection of high-energy harmonic and gamma-rays
- Double-crystal monochromator (Si 111): Band-pass filter



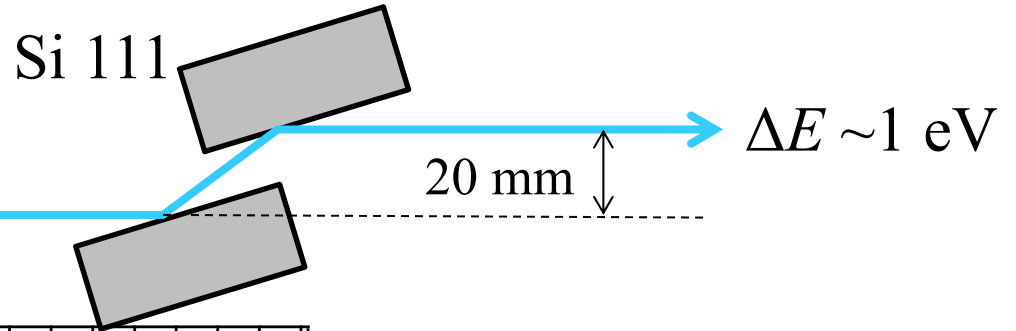
# Mirrors for harmonic rejection



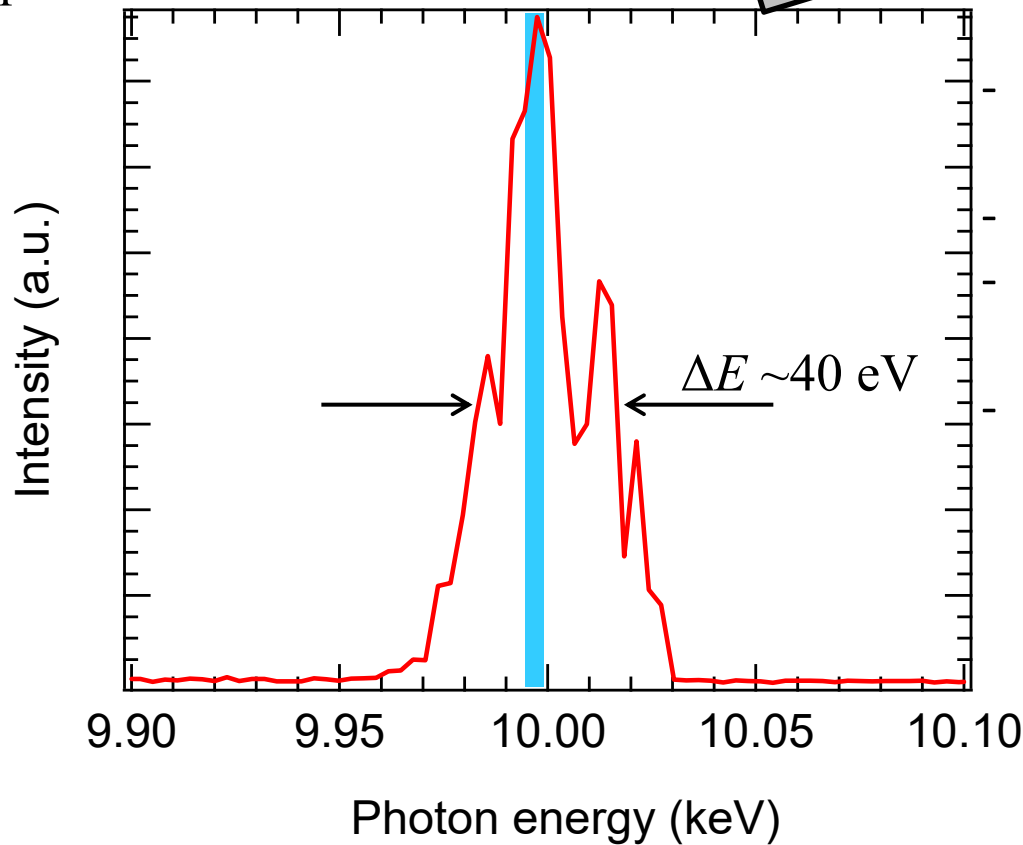
B.L. Henke, E.M. Gullikson, and J.C. Davis, Atomic Data and Nuclear Data Tables Vol. 54 (no.2), 181-342 (1993)

# Double-crystal monochromator

$$2d\sin\theta = \lambda$$



Spectrum at 10 keV

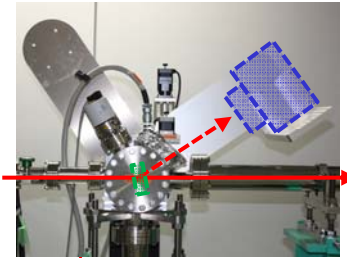


- Wavelength is tuned by rotating crystal
- Two crystals aligned in parallel
- Exit beam parallel to the incidence
- Same beam position along full wavelength range (small tuning of position)

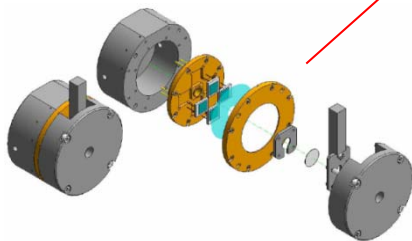
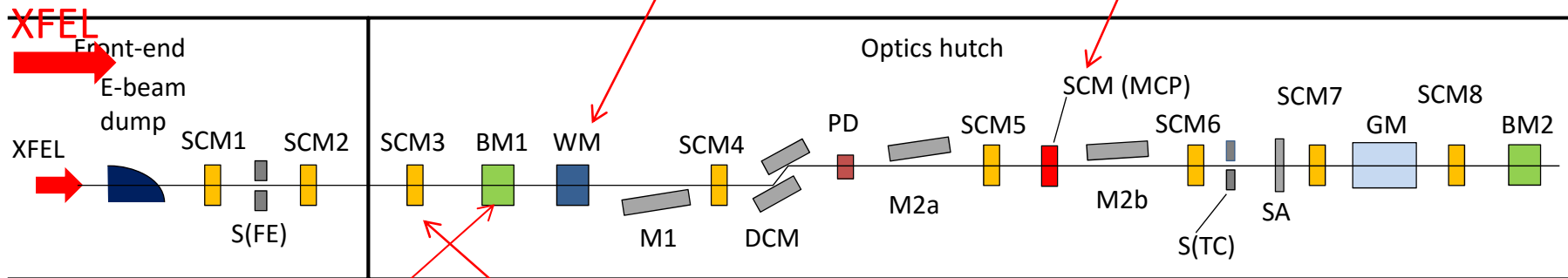


# X-ray Diagnostics

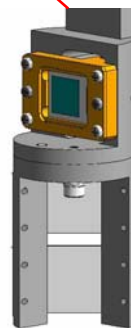
Wavelength monitor (ND)



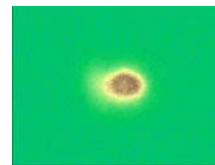
High-sensitivity screen monitor for spontaneous x-ray detection



Pulse energy x2



Screen monitor x7



Fixed point monitor for XFEL beam position with semi-transparent B-doped diamond;  $20 \mu\text{m}/100 \text{m} = 0.2 \text{ urad}$  accuracy

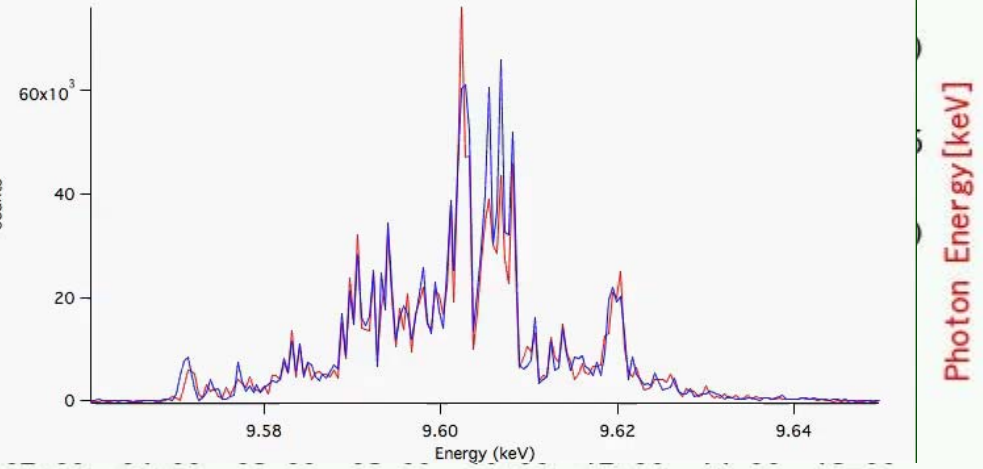
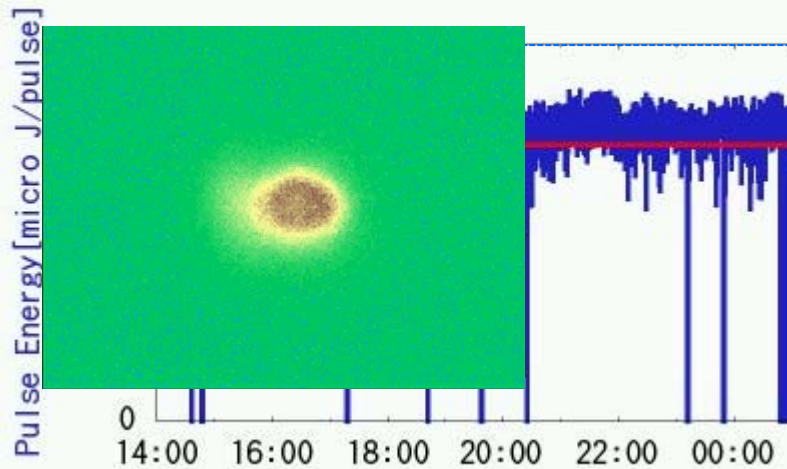
2015/9/25

# SACLA Operation Status

14:22:40

|                     |   |
|---------------------|---|
| Operation Mode      |   |
| BL3 User Operation  |   |
| Hutch in Use        |   |
| BL3 EH2             |   |
| Pulse Energy        | Photon Energy / Wavelength              |
| 230.9 micro J/pulse | 15.0 keV / 0.082 nm                     |
| Repetition Rate     | Intensity Fluctuation in 30 shots (STD) |
| 30 Hz               | 14.8 %                                  |

**~ 500 uJ @ 10 keV**  
**<10 fs pulse duration**



# Summary

- Connection between XFEL machine and beamline/optics becomes much important in advanced x-ray sources, including XFEL, DLSR and XFEL-O
- Tighter communications among electron & photon people (i.e., broader view) should significantly contribute to development of new light sources

# Acknowledgement

Drs. Shunji Goto, Kensuke Tono, Tetsuo Katayama, Yuichi Inubushi, (SPring-8/SACLA)

Thank you for your attention

*End*